



XAPP860 (v1.1) July 17, 2008

# 16-Channel, DDR LVDS Interface with Real-Time Window Monitoring

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## Summary

This application note describes a 16-channel, source-synchronous LVDS interface operating at double data rate (DDR). The transmitter (TX) requires 16 LVDS pairs for data and one LVDS pair for the forwarded clock. The transmitter operates at 6:1 serialization on each of the 16 data channels. The receiver (RX) also requires 16 LVDS pairs for data and one LVDS pair for the source-synchronous clock input. The receiver operates at 1:6 deserialization on each of the 16 data channels. The timing of the receiver is described in depth and characterized in hardware.

This application note is closely related to [XAPP855](#), *16-Channel DDR LVDS Interface with Per Channel Alignment*. The design technique discussed here has all of the same features, as well as an additional window monitoring circuit, boosting the performance above that of the design described in XAPP855. The added performance comes at the expense of additional logic utilization.

## Introduction

The design described in the application note targets a Virtex<sup>®</sup>-5 FPGA, taking advantage of the ChipSync<sup>™</sup> technology features available in every I/O of all Virtex-5 devices. These features include the ability to dynamically adjust the delay of the datapaths in the receiver with 78 ps resolution. Using this dynamic delay feature, the receiver in this application note escapes the limitations of static setup/hold timing by creating its own dynamic setup/hold timing. The interface calibrates out process variations by finding the optimal setup/hold timing for each individual device.

To calibrate out voltage and temperature variations, the interface continuously optimizes the setup/hold timing in real time. By calibrating out error due to process, supply voltage, and temperature (PVT), the interface can achieve the highest possible performance. The design described in *16-Channel DDR LVDS Interface with Per Channel Alignment* does not have a real-time window monitoring circuit to calibrate out supply voltage and temperature variations, and for that reason, has lower performance than the design described in this application note.

[Figure 1](#) shows a DDR interface in a Virtex-5 FPGA talking to a DDR interface in another device that can be either an ASIC or an FPGA with support for a 16-channel DDR interface. Since this is a source-synchronous link, the receivers of both devices receive their clock from the TX side of the other device. The clock sources for the transmitters could come from a number of places in the backend systems, such as an oscillator on the PCB. Since each of the 16 data channels on the serial side of the interface runs at 6:1 serialization, the data on the parallel side of the DDR interface is 96 bits.

The stand-alone DDR interface described in this application note does not include user constraints (includes no UCF file). To evaluate the performance of this DDR interface in hardware, a separate bit error rate tester (BERT) is also available for download ([Figure 2, page 2](#)).

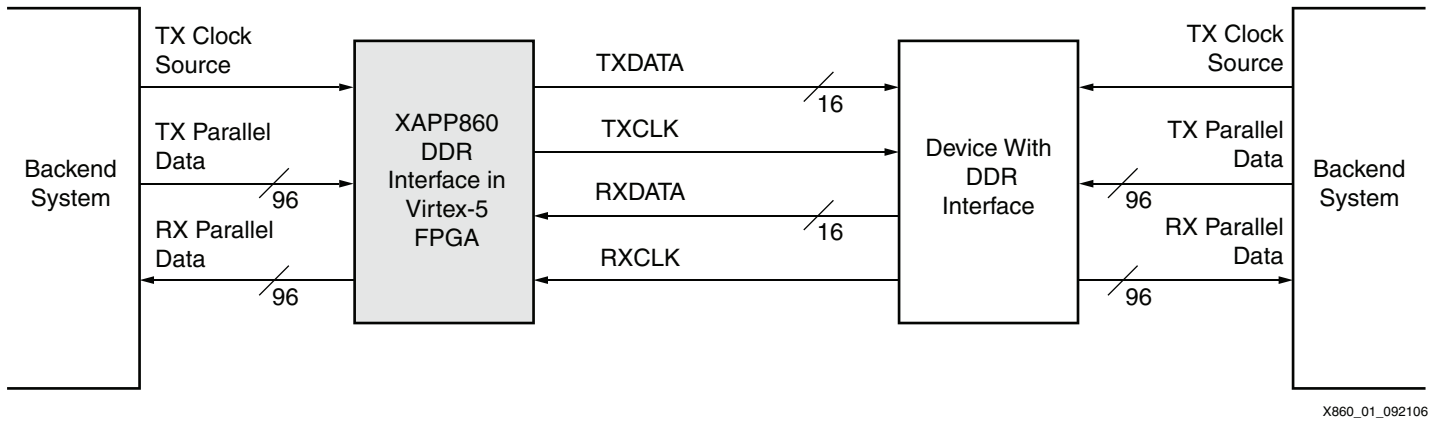


Figure 1: Full-Duplex, 16-Channel DDR Link between a Virtex-5 Device and Another Device with a 16-Channel DDR Interface

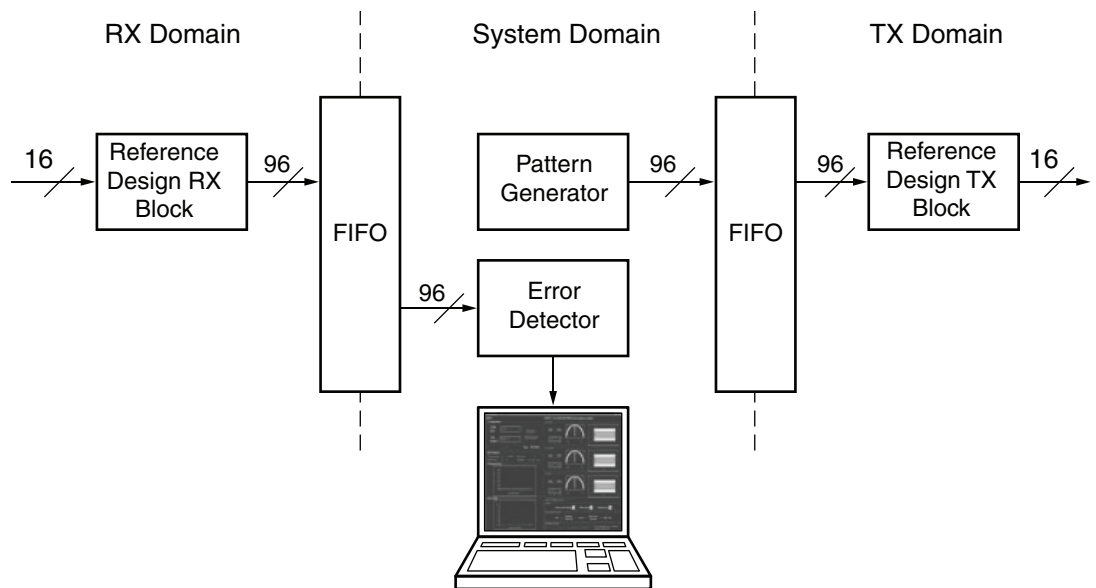
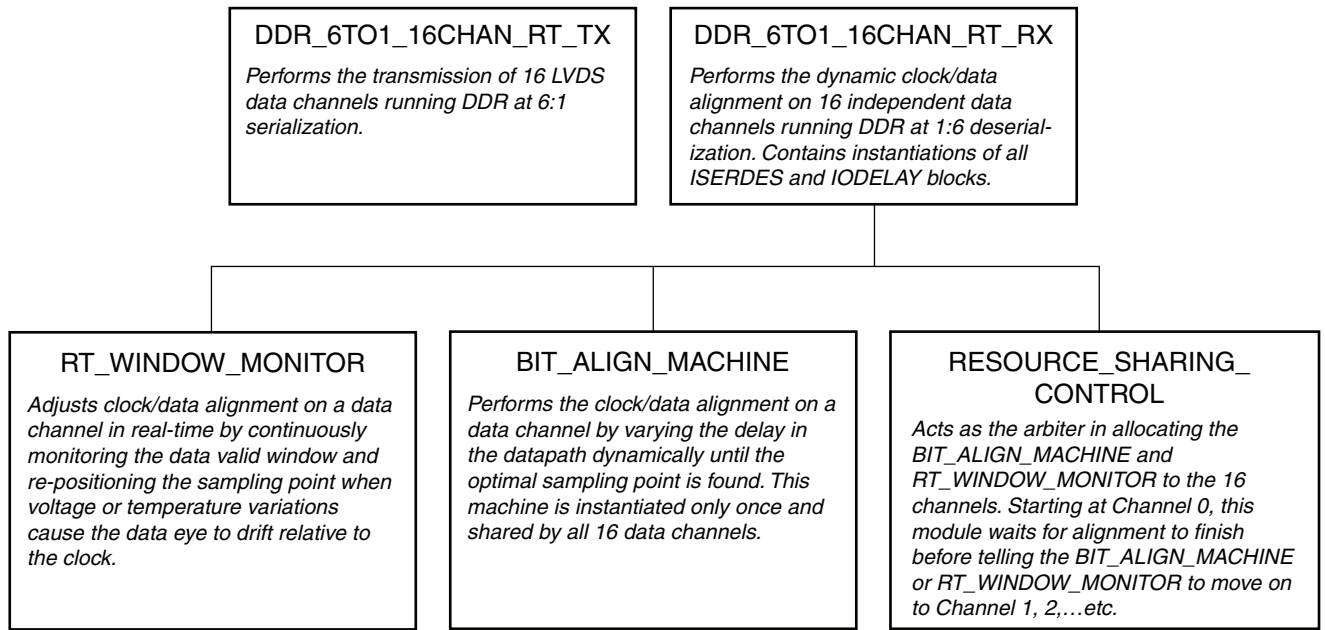


Figure 2: BERT Testbench for Hardware Verification of the DDR Interface

The BERT is a revision-controlled testbench and includes the latest version of the DDR interface. The Virtex-5 FPGA DDR transmitter is looped back to the DDR receiver in the same Virtex-5 device on an ML550 Networking Interfaces Board. The BERT communicates statistics about the interface performance to a graphical user interface on a PC. The BERT statistics are used extensively in the sections of this document concerned with hardware performance.

The design hierarchy of the interface itself is shown in Figure 3. The transmitter is very simple and contains almost no logic. The receiver contains logic that performs dynamic alignment and window monitoring on the 16 data channels.



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Figure 3: Design Hierarchy of the Interface (TX and RX)

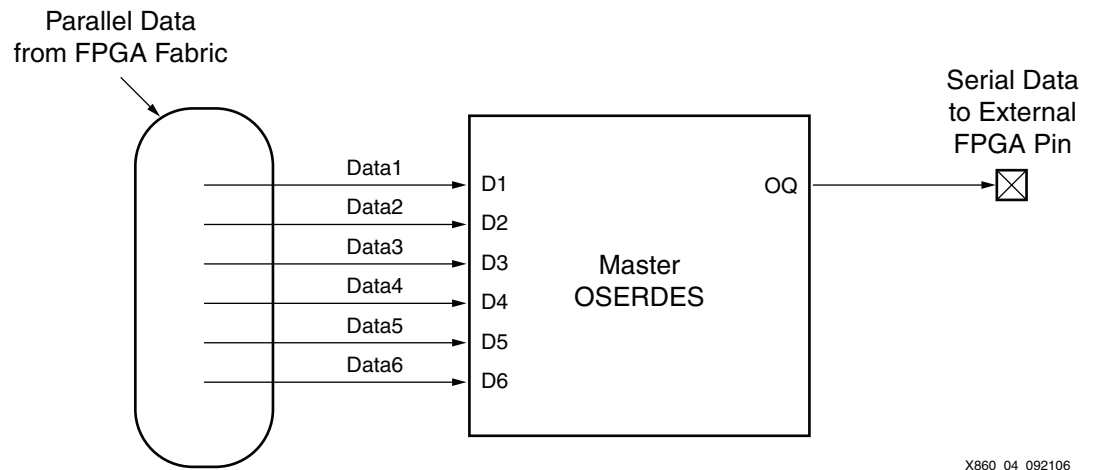
## DDR Transmitter

The DDR transmitter consists of only one module: **DDR\_6TO1\_16CHAN\_RT\_TX**. The module takes 96 bits of data on the parallel side, performs a 6:1 serialization, and transmits 16 channels of LVDS data on the serial side. The port list is shown in [Table 1](#).

Table 1: **DDR\_6TO1\_16CHAN\_RT\_TX** Module Port Definitions

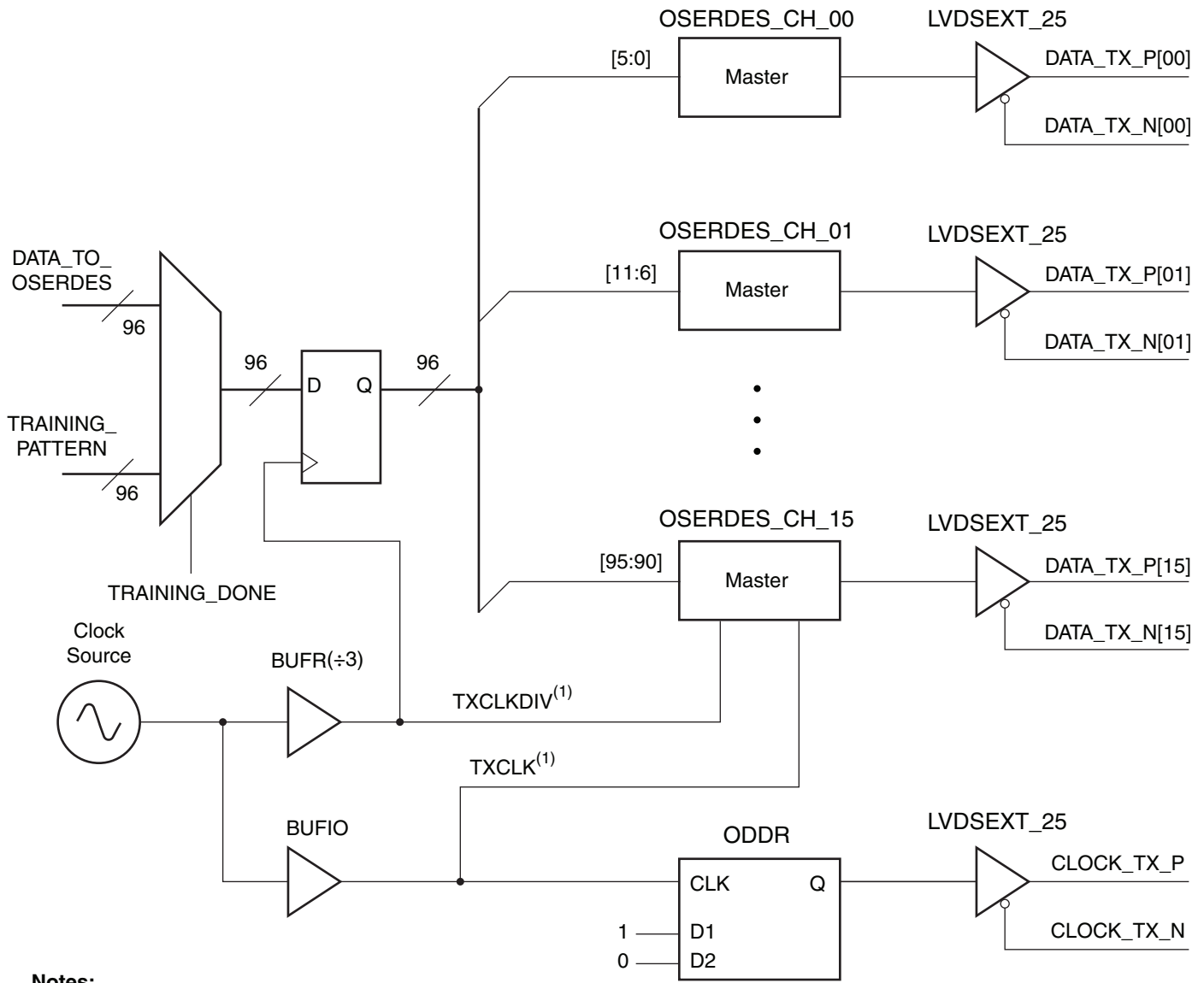
Port Name	I/O	Definition
DATA_TX_P [15:0]	Output	16 data channels (P)
DATA_TX_N [15:0]	Output	16 data channels (N)
CLOCK_TX_P	Output	Forwarded clock (P)
CLOCK_TX_N	Output	Forwarded clock (N)
TXCLK	Input	TX clock source
TXCLKDIV	Input	TX clock source divided by 3
DATA_TO_OSERDES [95:0]	Input	Parallel side data from backend system
RESET	Input	Reset synchronous to the TX domain
TRAINING_DONE	Input	Control signal telling the transmitter that receiver alignment is complete and user data can begin transmitting

Virtually no logic is used in the transmitter because all required functionality is contained within the OSERDES. The OSERDES is part of the ChipSync technology and is found in every I/O of all Virtex-5 devices. The OSERDES can be programmed to perform any serialization up to 10:1 and do single or double data rate transmission. For serializations greater than 6:1, a second OSERDES is needed (taken from the second I/O in the LVDS pair). The first OSERDES is called the master, and the second OSERDES is called the slave. Since this reference design runs at 6:1 serialization, only a single OSERDES is needed for each channel ([Figure 4](#)).



*Figure 4: Master OSERDES for a Single Data Channel with 6:1 Serialization*

The transmitter interface (Figure 5) consists of 16 master OSERDES such as the one shown in Figure 4. Since this interface is source synchronous, the clock must also be forwarded using the ODDR module.



**Notes:**

1. TXCLK and TXCLKDIV drive all OSERDES.

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Figure 5: Block Diagram of TX Interface

The only logic in the TX Interface is the multiplexer that selects between real data and the training pattern. Since this interface depends on dynamic alignment within the receiver, the transmitter is required to send a training pattern until the receiver completes the initial alignment process on all 16 channels. In the design described in this application note, the select line to that multiplexer is assumed to be connected to a feedback signal from the receiver interface. If a feedback signal from the RX interface is undesirable, the MUX select line can be tied to a timer that grants the receiver a fixed amount of time to complete alignment. For example, the transmitter can transmit the training pattern for 500 ms, after which it assumes that the receiver alignment process is complete and sends real data.

Table 2 shows the device utilization statistics for the TX interface implemented in a Virtex-5 device. Since there is no combinatorial logic in the transmitter, no look-up tables (LUTs) are used. The 96-bit MUX is implemented using only 96 flip-flops and no combinatorial logic. Table 2 also shows one BUFR and one BUFR being used. This design can also be implemented using two BUFGs and a DCM instead. The different clocking options for this interface are discussed in "Interface Clocking."

Table 2: DDR TX Interface Utilization Statistics

Component	Quantity	Usage Description
Slice Flip-Flop	96	Registered MUX output of DATA_TO_OSERDES
Slice	24	96/4 FFs per slice = 24 slices
LUT	0	–
IOB	34	17 LVDS output pairs (16 data, 1 clock)
OSERDES	16	Master OSERDES for every LVDS data pair
BUFIO	1	TXCLK
BUFR	1	TXCLKDIV

## Interface Clocking

In the block diagram of the DDR transmitter shown in [Figure 5, page 5](#), the clock networks are shown driven by BUFIO and BUFR. When BUFIO and BUFR are used to generate the serial and parallel clocks, the phase relationship between the two clocks is guaranteed by design to meet the input requirements of the OSERDES (and ISERDES). Another valid way of driving the clock networks in [Figure 5](#) is to use global clocks combined with either a DCM or a PLL to provide the serial and parallel clocks. The DCM and PLL schemes also provide phase-matched clock outputs, guaranteed by design to meet the input requirements of the OSERDES (and ISERDES). The three valid clocking schemes are shown in [Figure 6](#).

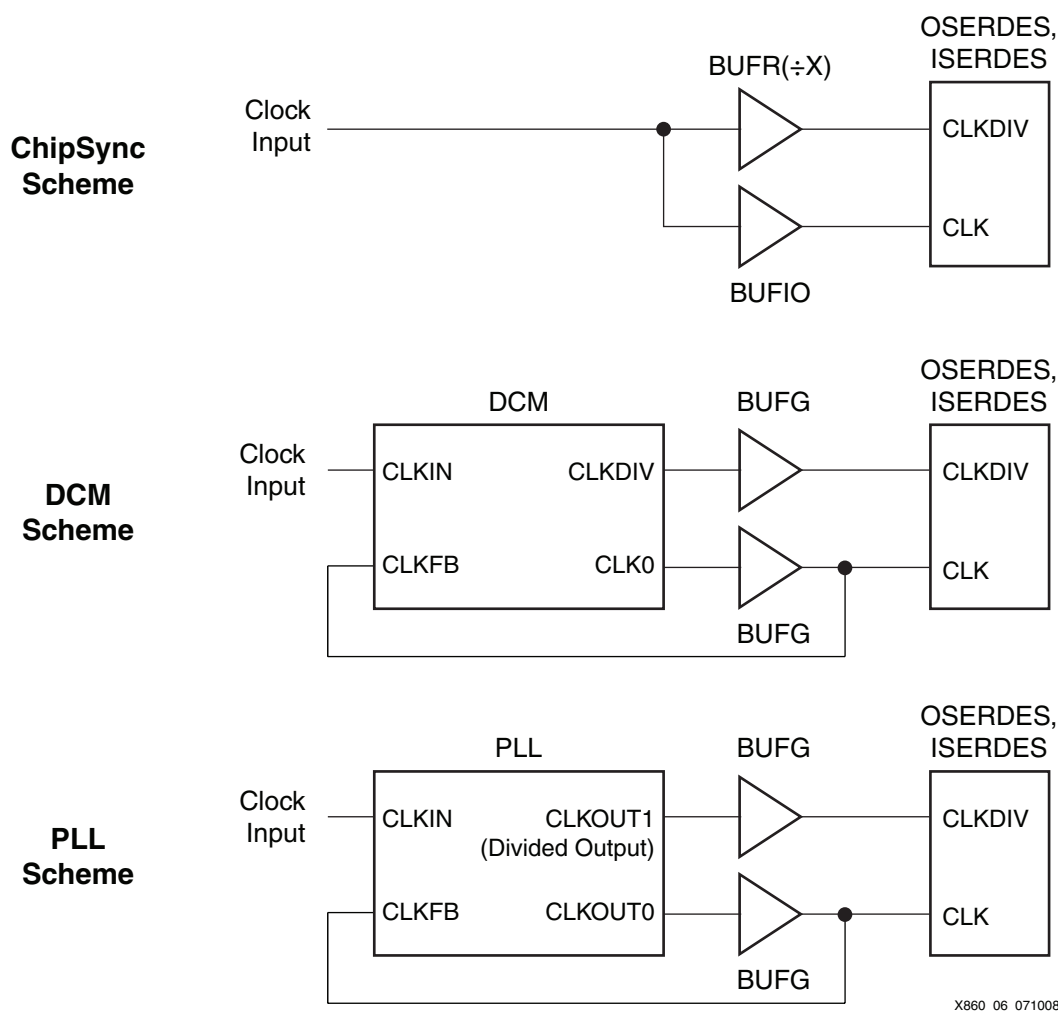


Figure 6: Global and Regional Clocking Schemes in Virtex-5 FPGAs

Which clocking scheme is the best to use? The BUFIO/BUFR networks maximize performance at the expense of some convenience. BUFIO and BUFR are regional clocks that cannot span the entire chip like a global clock. This difference means that transferring data between the regional and global domains must be a part of the designer's task and can simply mean adding a FIFO between the clock domains.

Global clocks have lower performance than BUFIO, but are more convenient to use. If a clock is placed on a global network, it can reach any component in the entire device. To show the performance advantage of BUFIO, Table 3 shows snapshots of several timing parameters, some of which are included in the timing budget calculations for source synchronous interfaces. In each case, BUFIO has an advantage over BUFG, and collectively those advantages are significant. These parameters are used in the timing budget calculation section, "Interface Timing Budget," page 25. For the most current specifications, always consult the data sheet on [www.xilinx.com](http://www.xilinx.com).

Table 3: Comparison of Global and I/O Clock Performance by Speed Grade

	-3	-2	-1	Units
<b>Maximum Frequency</b>				
BUFG $F_{MAX}$	(see note)	(see note)	(see note)	MHz
BUFIO $F_{MAX}$	710	710	644	MHz

Table 3: Comparison of Global and I/O Clock Performance by Speed Grade (Continued)

	-3	-2	-1	Units
<b>Duty Cycle Distortion</b>				
BUFG DYCD	120	120	120	ps
BUFIO DYCD	100	100	100	ps
<b>Sampling Error</b>				
BUFG T <sub>SAMP</sub>	450	500	550	ps
BUFIO T <sub>SAMP</sub>	350	400	450	ps
<b>Clock Tree Skew</b>				
BUFG skew for XC5VLX50T	260	270	280	ps
BUFIO skew for all devices	70	70	80	ps

**Notes:**

1. Refer to [DS202](#), *Virtex-5 FPGA Data Sheet: DC and Switching Characteristics* for the maximum performance of the BUFG.

Since this reference design has high performance targets (see [Table 15, page 32](#)), those targets can be difficult or impossible to meet using a global clocking scheme. To offer the maximum performance, the interface described in this application note uses a BUFIO/BUFR clocking scheme in both the transmitter and receiver. The interface does not include the FIFO logic necessary to transfer the parallel data to/from the backend system domain. However, the BERT design discussed in “[Introduction](#),” [page 1](#) (see [Figure 2, page 2](#)) shows how to transfer data to/from the RX and TX clock domains by using a FIFO18\_36 primitive.

## DDR Receiver

The DDR receiver consists of four core modules: DDR\_6TO1\_16CHAN\_RT\_RX, BIT\_ALIGN\_MACHINE, RT\_WINDOW\_MONITOR, and RESOURCE\_SHARING\_CONTROL. The receiver is more complex than the DDR transmitter because it includes both dynamic alignment and window monitoring algorithms implemented in the FPGA fabric. The DDR\_6TO1\_16CHAN\_RT\_RX module takes 16 channels of data on the serial side, optimizes the timing relationship of each channel with the clock, performs 1:6 deserialization, presents 96 bits of data on the parallel side, and continuously monitors the data window to ensure optimal sampling. The port list is shown in [Table 4](#).

Table 4: DDR\_6TO1\_16CHAN\_RT\_RX Module Port Definitions

Port Name	I/O	Definition
DATA_RX_P [15:0]	Input	16 data channels (P).
DATA_RX_N [15:0]	Input	16 data channels (N).
CLOCK_RX_P	Input	Forwarded clock (P).
CLOCK_RX_N	Input	Forwarded clock (N).
INC_PAD	Input	Pulsing this pin causes the IDELAY tap setting of all data channels to increment by 1.
DEC_PAD	Input	Pulsing this pin causes the IDELAY tap setting of all data channels to decrement by 1.
DATA_FROM_ISERDES [95:0]	Output	Parallel side data to backend system.
RESET	Input	Reset synchronous to the RX domain.
IDLY_RESET	Input	Reset synchronous to the RX domain that only resets the IDELAY tap settings of all data channels.

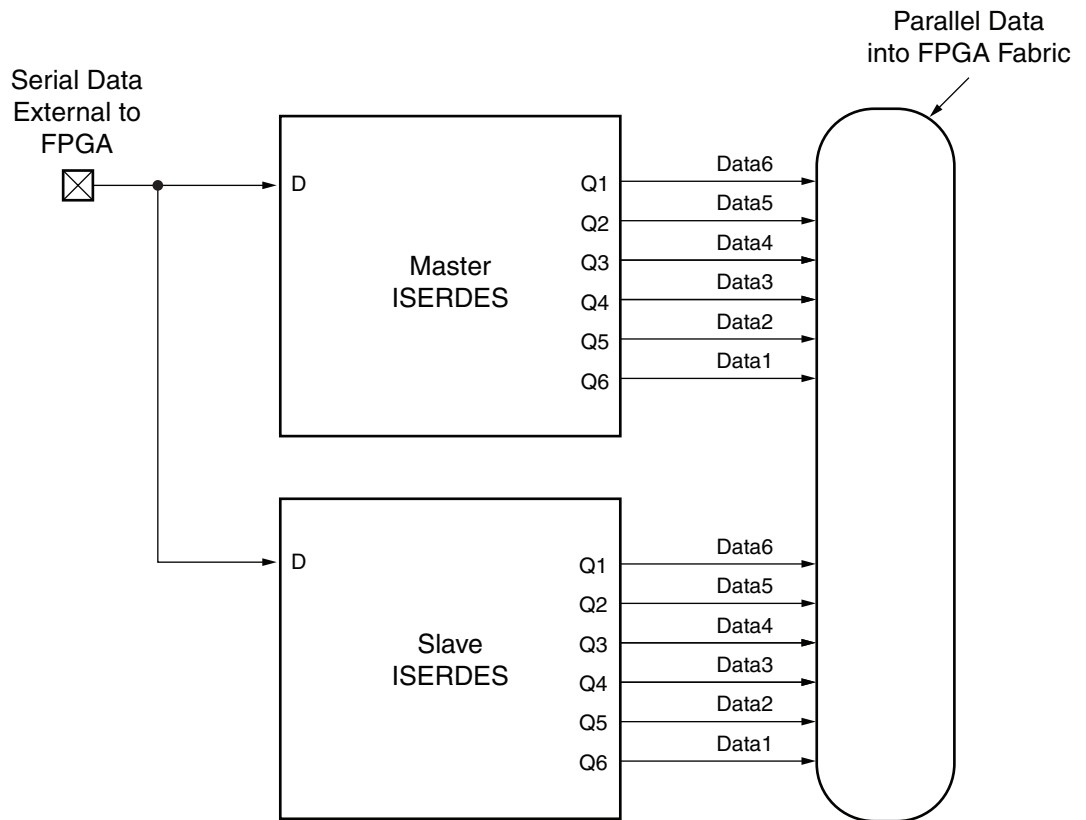


Table 4: DDR\_6TO1\_16CHAN\_RT\_RX Module Port Definitions (Continued)

Port Name	I/O	Definition
IDELAYCTRL_RESET	Input	Reset synchronous to the TX domain that only resets the IDELAYCTRL module.
BITSLIP_PAD	Input	Pulsing this pin causes one bit slip operation on all data channels.
CLK200	Input	Reference clock to IDELAYCTRL module.
TAP_00, TAP_01, TAP_03, TAP_04, TAP_05, TAP_06, TAP_07, TAP_08, TAP_09, TAP_10, TAP_11, TAP_12, TAP_13, TAP_14, TAP_15	Output[5:0]	Each of these 6-bit signals contains the current IDELAY tap value of the sixteen data channels. Possible values: 0-63.
TAP_CLK [5:0]	Output	The 6-bit signal containing the current IDELAY tap value of the clock channel. Permanently set to zero because the clock channel is not adjusted.
TRAINING_DONE	Output	Flag indicating alignment is complete.
RXCLK	Output	RX Source Sync Clock.
RXCLKDIV	Output	RX Source Sync Clock divided by 3.
IDELAY_READY	Output	Flag indicating IDELAYCTRL is calibrated.
RT_MANUAL_DISABLE	Input	Holding this pin High disables the real-time window monitoring circuit, such that no dynamic adjustments to data channels occur.

Most of the logic used in the receiver is contained within the ISERDES. The ISERDES is part of the ChipSync technology and is found in every I/O of all Virtex-5 devices. The ISERDES can be programmed to do any deserialization up to 1:10 and do single or double data rate reception. For deserializations greater than 6:1, a second ISERDES is needed (taken from the second I/O in the LVDS pair). The first ISERDES is called the master, and the second ISERDES is called the slave.

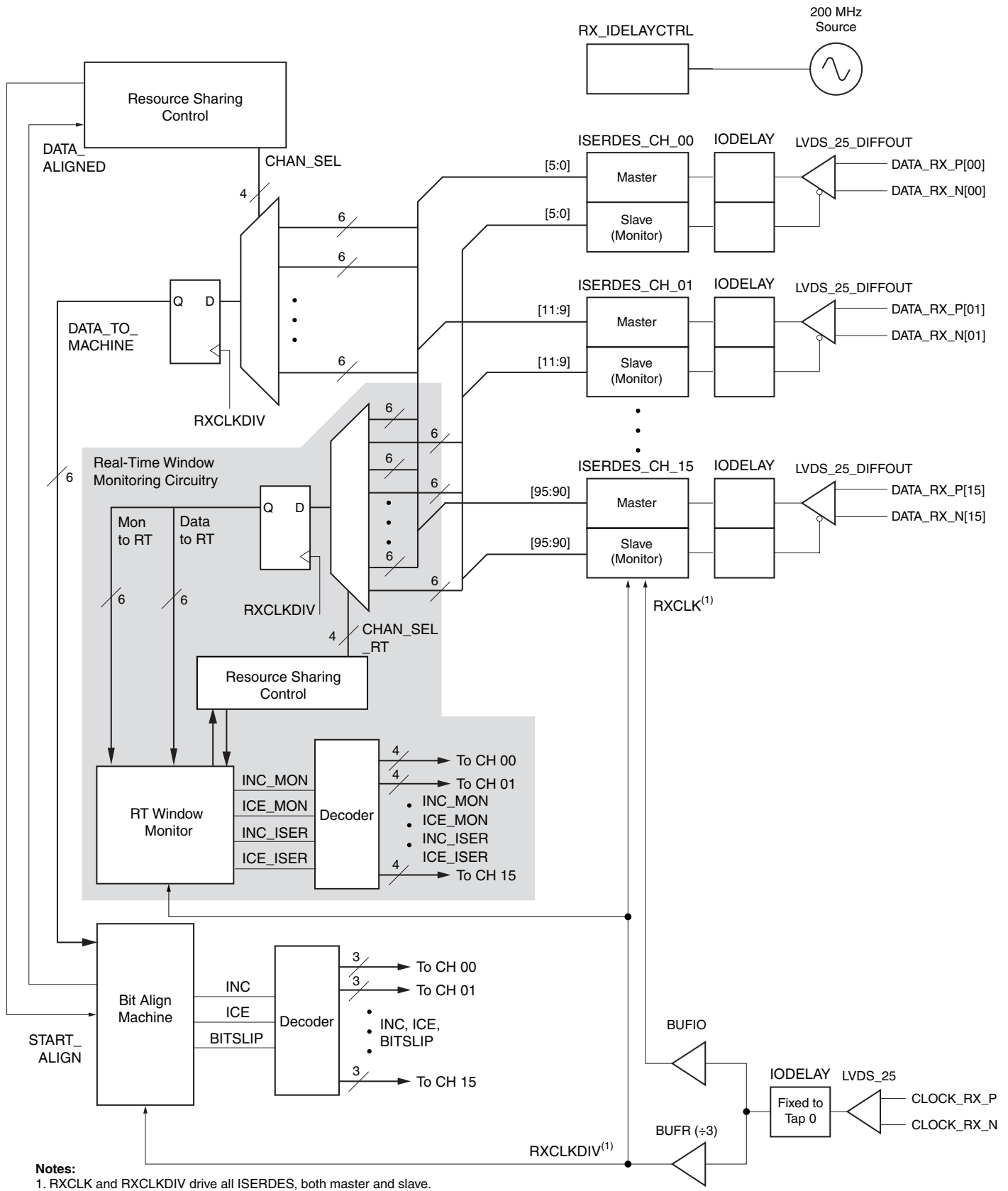
However, the implementation of the window-monitoring circuit places a restriction on the serialization ratios that can be used. 6:1 is the highest serialization factor that can be used in conjunction with the circuit described in this application note. To achieve serialization factors such as 8:1 or 10:1, both a master and slave SERDES are required. However, the window-monitoring circuit depends upon using the slave ISERDES as a "mirror" of the master ISERDES, thereby rendering it unavailable to do the higher serializations. The use of the slave ISERDES as a mirror of the master ISERDES is shown in [Figure 7](#).



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**Figure 7: Master/Slave ISERDES Pair for a Single Data Channel with 1:6 Deserialization**

The receiver interface (Figure 8) consists of 16 master/slave ISERDES pairs. Since this interface is source synchronous, the clock source comes from the transmitter. The clock is buffered in the receiver by a BUFIO component and divided to the parallel clock rate by a BUFR component.



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Figure 8: Block Diagram of RX Interface

Each ISERDES in [Figure 8, page 11](#) contributes 6 bits to the 96-bit parallel data bus. Since there is only one instance of BIT\_ALIGN\_MACHINE in the receiver, each data channel must be aligned separately by sharing that resource. The 8-bit data buses from each ISERDES are fed into a MUX that selects which of the 16 channels has access to the BIT\_ALIGN\_MACHINE resource. RESOURCE\_SHARING\_CONTROL controls the MUX to ensure that every channel completes its alignment before the MUX switches to the next channel. The START\_ALIGN signal tells the BIT\_ALIGN\_MACHINE that alignment can begin on the current channel because the MUX output is stable. The DATA\_ALIGNED signal tells the RESOURCE\_SHARING\_CONTROL module that alignment on the current channel is complete.

Similarly, there is only one instance of RT\_WINDOW\_MONITOR, shared among the 16 channels. A second RESOURCE\_SHARING\_CONTROL module is used to allocate the RT\_WINDOW\_MONITOR circuit. This RESOURCE\_SHARING\_CONTROL module is different from the module that allocates the BIT\_ALIGN\_MACHINE in the sense that the BIT\_ALIGN\_MACHINE only operates once on each channel, while RT\_WINDOW\_MONITOR must operate indefinitely on all channels. One full excursion through all 16 channels takes roughly 10  $\mu$ s, such that each channel's timing is optimized at least once every 10  $\mu$ s. This refresh rate is sufficient to track out timing variation caused by voltage and temperature drift that occurs over a period of seconds, minutes, hours, or days. The circuit is not designed to withstand large, instantaneous changes in supply voltage, for example, an instantaneous drop of 5%. In most cases, the circuit can withstand even large, instantaneous variations, but it is not guaranteed to do so. Temperature cannot be varied fast enough to be an issue.

The order of the parallel data outputs of the ISERDES is the opposite of the parallel data inputs of the OSERDES ([Figure 4, page 4](#) versus [Figure 7](#)).

The IDELAYCTRL module in [Figure 8](#) is shown as having no connection to the rest of the receiver. Actually, IDELAYCTRL is required to calibrate the IODELAY blocks in the path of each data channel. A single IDELAYCTRL block is sufficient to calibrate all 16 data channels, since all channels are in the same bank.

The BIT\_ALIGN\_MACHINE generates three control signals that adjust the timing of the appropriate ISERDES. INC and ICE cause the IODELAY to increment or decrement the delay in the datapath by a fixed amount of ~78 ps (if a 200 MHz reference clock is used). BITSLLIP causes each ISERDES to rotate the order of the parallel output data bits, facilitating the process of word alignment. These three control signals are directed to the appropriate ISERDES by the decoder shown in [Figure 8](#). Although not shown in the figure, the decoder is also controlled by the RESOURCE\_SHARING\_CONTROL module.

The RT\_WINDOW\_MONITOR generates four control signals: INC\_MON, ICE\_MON, INC\_ISER, and ICE\_ISER. INC\_MON and ICE\_MON go to all 16 monitor ISERDES and allow for the interrogation of the monitor data eye without disrupting the user traffic on the master channel. INC\_ISER and ICE\_ISER are the adjustment controls for the master (and monitor) ISERDES channels. These signals are only asserted when the RT\_WINDOW\_MONITOR detects that the sampling point has drifted close to an invalid portion of the data window.

[Table 5](#) shows the device utilization statistics for the RX interface implemented in a Virtex-5 device. These figures exclude the counters used to track the IODELAY settings on all data channels; in most instances, those counters can be removed after the interface is integrated and verified in a specific environment. The majority of the LUTs utilized are consumed by the BIT\_ALIGN\_MACHINE and RT\_WINDOW\_MONITOR, which are the core of the receiver alignment algorithm. As in the TX interface, the RX interface consumes one BUFIO and one BUFR for clocking. The clocking could also be accomplished using BUFGs and a DCM as described in ["Interface Clocking," page 6](#), but the performance/convenience trade off would need to be considered.

Table 5: DDR RX Interface Utilization Statistics

Component	Quantity	Usage Description
Slice Flip-Flop	247	Multiple uses
Slice	206	Multiple uses
LUT	498	Multiple uses
IOB	34	17 LVDS input pairs (16 data, 1 clock)
ISERDES	32	Master and slave ISERDES for every LVDS data pair
BUFIO	1	RXCLK
BUFR	1	RXCLKDIV

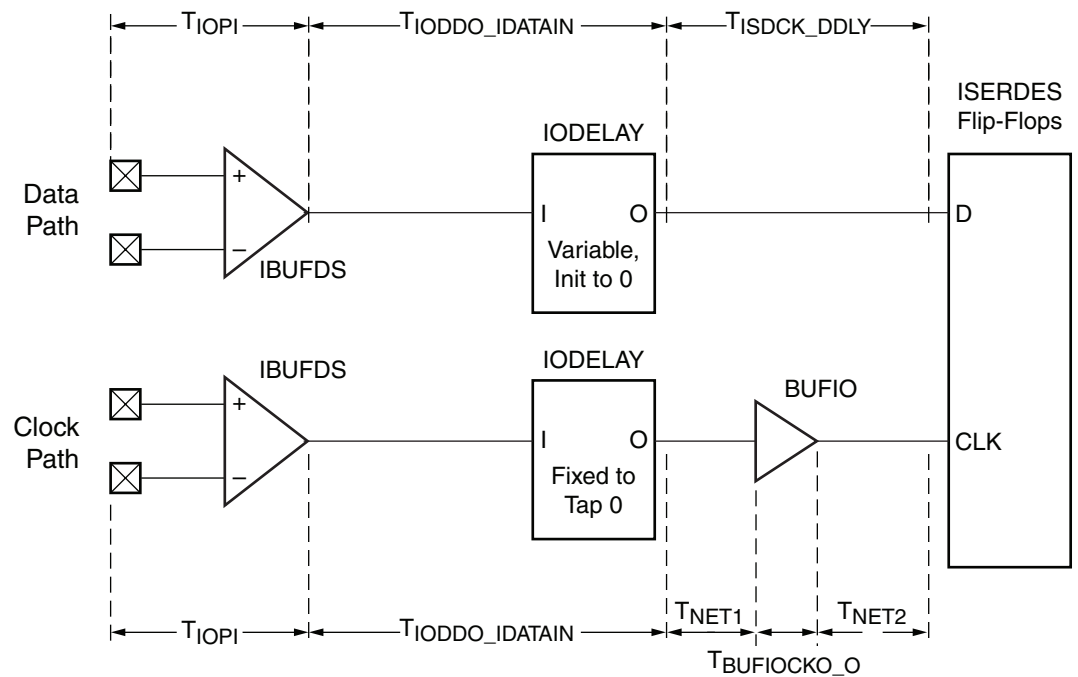
## Receiver Interface Dynamic Timing

The timing of the receiver interface is broken into three parts:

- The suboptimal timing inherent in the data and clock paths
- The optimal timing created by the receiver when adjusting dynamic delays on each of the 16 data channels at initialization.
- The ongoing timing optimization performed by the receiver in real-time (window monitoring).

### Inherent Timing

An inventory of all propagation delays in the clock and datapaths must be taken to derive the inherent setup/hold times. The clock and datapaths for a single channel of this interface are shown in Figure 9. The ISE Timing Analyzer breaks down the paths into the timing parameters shown. All components in the path have both a minimum and maximum value to account for process variations.



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Figure 9: Timing Components of RX Data and Clock Paths

Figure 10, page 14 shows the timing analyzer settings used to generate the information in this report. Each of the timing parameters is described in Table 6, page 14 and Table 7. The minimum

and maximum values of the individual timing parameters for the clock and datapaths are shown in [Table 8](#) and [Table 9](#), page 15.

**Note:** All raw timing numbers referenced in this document are subject to minor changes in subsequent revisions of the ISE tools.

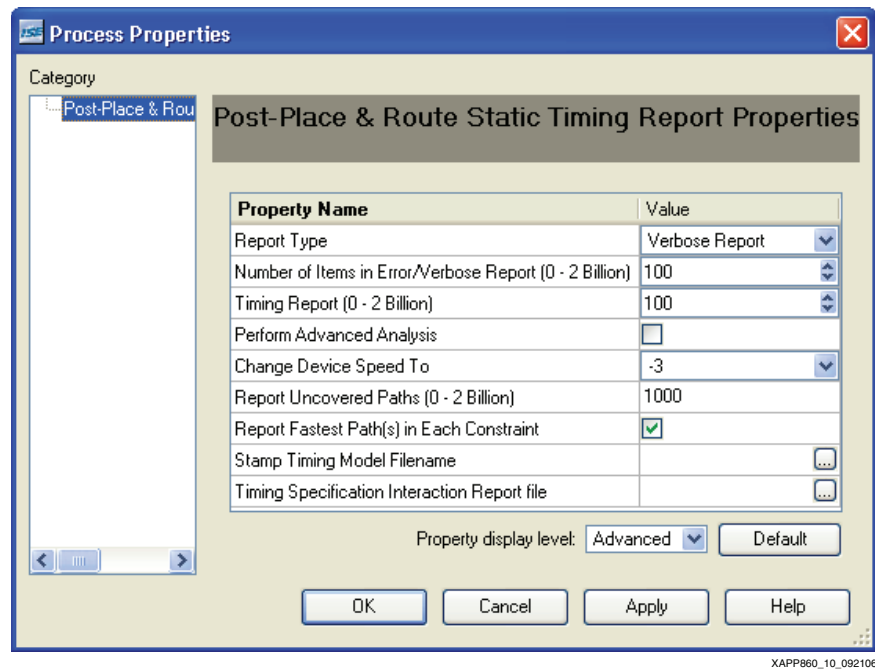


Figure 10: ISE Timing Analyzer Properties Used in this Document

Table 6: Datapath Timing Definitions

Timing Parameter	Description
$T_{IOP1}$	Delay from the IOB pad through the LVDS input buffer to the I pin of the IOB pad
$T_{IODDO\_IDATAIN}$	Delay from the I pin of IOB pad to the D input of the ISERDES
$T_{ISDCK\_DDL Y}$	Delay from the D input of the ISERDES to the sampling registers in the ISERDES (setup and hold times of ISERDES)

Table 7: Clock Path Timing Definitions

Timing Parameter	Description
$T_{IOP1}$	Delay from the IOB pad through the LVDS input buffer to the I pin of the IOB pad
$T_{IODDO\_IDATAIN}$	Delay from I pin of IOB pad to the O output of the IODELAY block
$T_{NET1}$	Delay from the O output of the IODELAY block to the I pin of BUFIO
$T_{BUFIOCKO\_O}$	Clock to out delay of BUFIO
$T_{NET2}$	Clock distribution delay from BUFIO output to the clock input of data ISERDES

Table 8: Datapath Delay Inventory for a -1 Speed Grade XC5VLX50T Device

Timing Parameter	Maximum Datapath Delay	Minimum Datapath Delay
$T_{IOP1}$	1.083 ns	0.763 ns
$T_{IODDO\_IDATAIN}$	0.671 ns	0.671 ns

Table 8: Datapath Delay Inventory for a -1 Speed Grade XC5VLX50T Device (Continued)

Timing Parameter	Maximum Datapath Delay	Minimum Datapath Delay
T <sub>ISDCK_DDLY</sub>	0.064 ns	-0.038 ns
TOTAL	1.818 ns	1.396 ns

Table 9: Clock Path Delay Inventory for a -1 Speed Grade XC5VLX50T Device

Timing Parameter	Maximum Clock Path Delay	Minimum Clock Path Delay
T <sub>IOP1</sub>	1.150 ns	0.820 ns
T <sub>IODDO_IDATAIN</sub>	0.671 ns	0.671 ns
T <sub>NET1</sub>	0.254 ns	0.190 ns
T <sub>BUFIOCKO_O</sub>	1.130 ns	0.894 ns
T <sub>NET2</sub>	0.404 ns	0.319 ns
TOTAL	3.609 ns	2.894 ns

According to the inherent timing prediction, the data is going to arrive before the clock by an amount determined by Equation 1 and Equation 2. Equation 1 calculates that data arrives before the clock by at least 1.076 ns in a -1 device. Equation 2 calculates that data arrives before the clock by at most 2.213 ns. Equation 3 shows a timing window that covers all -1 devices under all conditions. This timing window describes the inherent timing of the data and clock paths. Assuming skew-matched PCB traces for all sixteen channels, it can be assumed that all 16 channels in the receiver have roughly the same timing window.

$$\text{Setup Time} = \text{Max Data Delay} - \text{Min Clock Delay} = 1.818 - 2.894 = -1.076 \text{ ns} \quad \text{Equation 1}$$

$$\text{Hold Time} = \text{Max Clock Delay} - \text{Min Data Delay} = 3.609 - 1.396 = 2.213 \text{ ns} \quad \text{Equation 2}$$

$$\text{Timing Window} = 2.213 - 1.076 = 1.137 \text{ ns} \quad \text{Equation 3}$$

Figure 11 shows the timing windows for all speed grades of an XC5VLX50T device as well as a hardware measurement of the inherent timing relationship (to validate the calculations). The hardware measurement shows the DDR interface data arriving 1.425 ns before the clock, which by inspection, places the device in all three speed grade ranges (the device used for the hardware measurement is a -2 device).

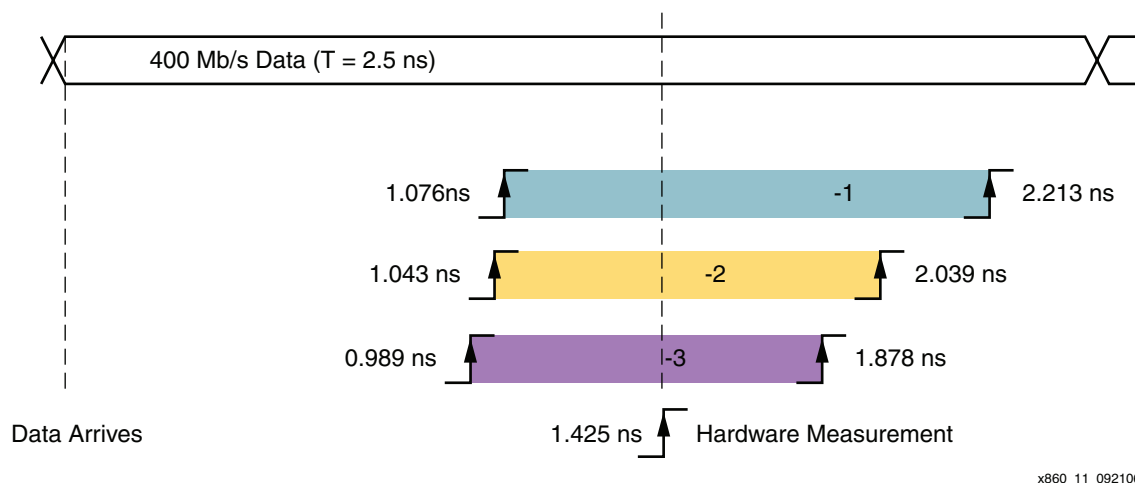


Figure 11: Timing Windows Show Uncertainty in Clock/Data Relationship as Calculated by Timing Analyzer

## Dynamic Timing and BIT\_ALIGN\_MACHINE

In “Inherent Timing,” page 13, the inherent timing of the interface was calculated for all speed grades and validated with a hardware measurement. In that case, the inherent timing was sufficient because the data rate is only 400 Mb/s (Figure 11, page 15). What happens when the data rate is increased such that the hold edge of the data window begins to shrink (Figure 12)?

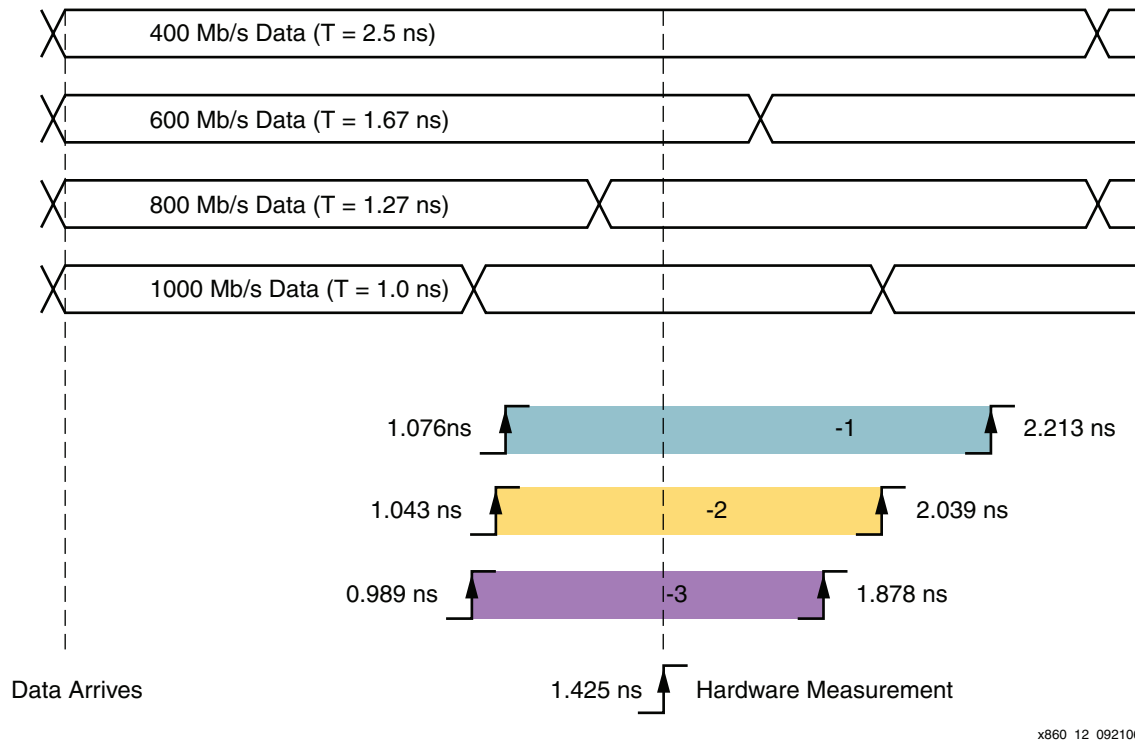


Figure 12: Inherent Timing Windows Shown in Relation to Multiple Data Rates

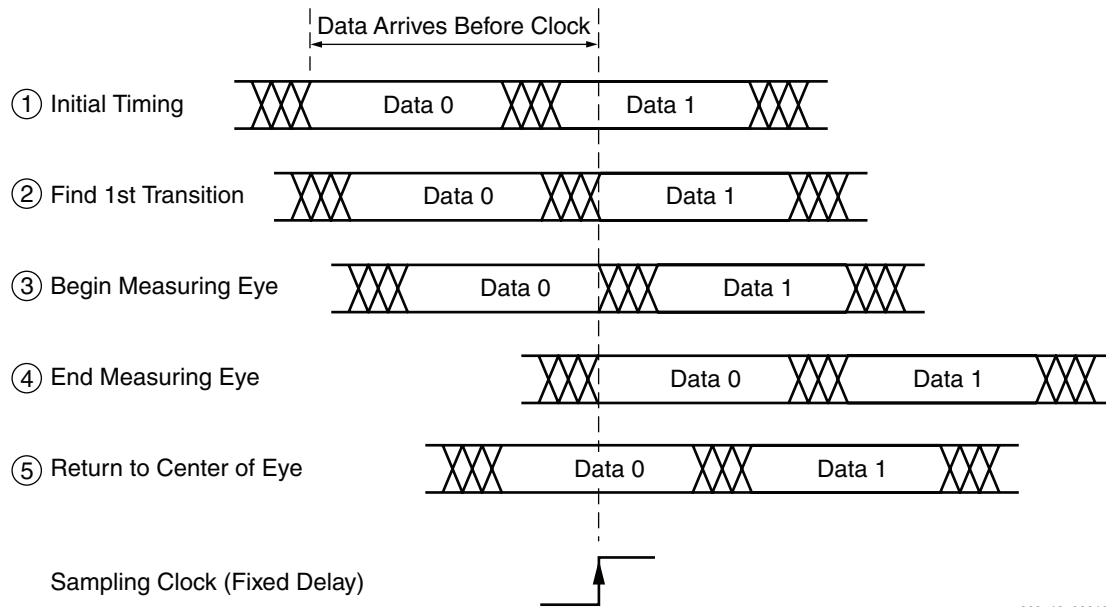
At 600 Mb/s, the inherent timing relationship is no longer adequate to meet timing because there are cases when the sampling clock edge is in the middle of the data transition. As the data rates increase to 800 and 1000 Mb/s, the clock actually captures the data arriving one bit time later. For designs that are sensitive to word alignment, this is unacceptable.

The solution to the suboptimal, inherent timing is dynamic timing. The BIT\_ALIGN\_MACHINE module in the receiver performs two functions of dynamic timing:

- **Bit Alignment:** Position the sampling edge of the clock at the center of the data eye by adding delay to the datapaths during initialization.
- **Word Alignment:** Ensure that the parallel data bits are in the correct order at the output of the ISERDES by using the bitslip function in the ISERDES.

The steps of the bit-alignment procedure are shown in Figure 13, page 17. Each step of the algorithm can either add or subtract delay from the datapath. All 16 channels are taken through this procedure independently. This procedure measures one full data eye (in terms of 78 ps delay taps) and then returns to the center of the data eye. Steps 1 and 2 are dedicated to moving through the partial eye of the initial timing, while steps 3 and 4 are dedicated to measuring a full eye. Step 5 is dedicated to positioning the clock edge at the center of the data eye.





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Figure 13: Dynamic Bit-Alignment Procedure in BIT\_ALIGN\_MACHINE

Jitter is represented in Figure 13 as multiple transition lines. Accounting for jitter is a crucial part of the algorithm. In step 2, the first data transition is found. If there is no jitter, the eye measurement can begin instantly after finding the transition. However, when jitter is considered, the algorithm must find the first transition, move through the transition, and then begin looking for the second transition. If the algorithm does not move through the first transition intelligently, it runs the risk of falsely detecting the second transition.

After bit alignment is complete, the order of the data bits can be adjusted to achieve word alignment. The bit-alignment procedure ensures that data is being sampled correctly, but the order of the data can be a few bits off from where the receiver expects it to be. To correct this, the bitslip feature of the ISERDES is used to "slip" bit times until the proper alignment is found. For this feature to be useful, a training pattern must be generated by the transmitter (as discussed in "DDR Transmitter," page 3) that the receiver can use to determine the proper word alignment. In this reference design, the training pattern is 101100 (0x2C). This pattern is mostly arbitrary, as many other patterns work just as well. This pattern was chosen because a training pattern should behave electrically as much like real data as possible, such that the center of the training eye is the center of the data eye. Since real data contains strings of consecutive ones and zeros, it is best for the training pattern to do the same. For that reason, a 0x2C pattern is better than an 0x2A pattern because it contains run lengths of 1- and 2-bit times.

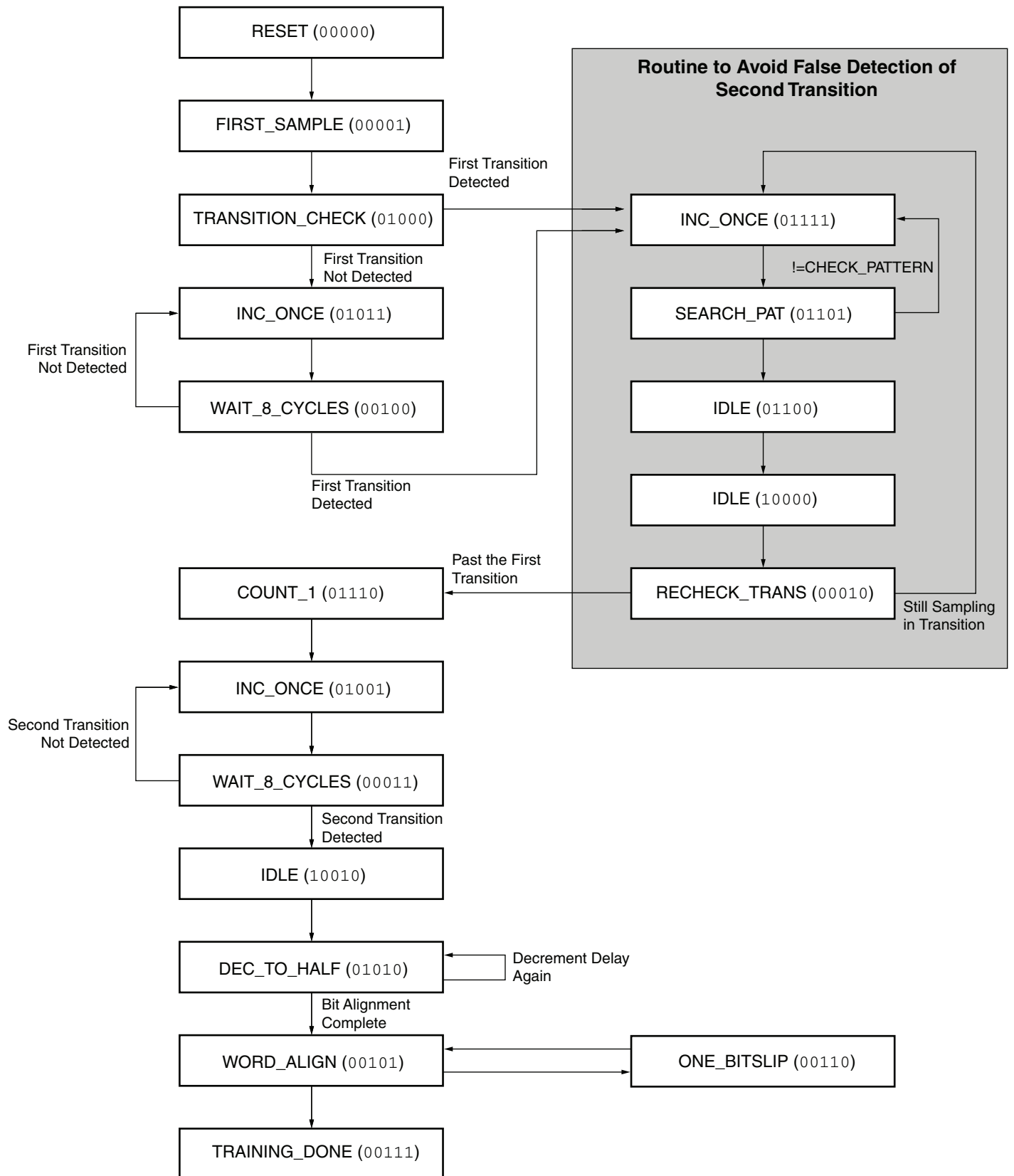
Table 10, page 18 shows the word-alignment process in the case where bit alignment completes with the data outputs set to 0x19. Since 0x19 is not the training pattern the receiver is looking for, bitslip is asserted until 0x2C is found. This reference design uses a 1:6 deserialization, so there are only six possible configurations of the parallel data outputs. If bitslip is asserted infinitely, the same six configurations will repeat. Bitslip in DDR mode is somewhat irregular because it does not simply rotate by one bit on every bitslip cycle. This effect is inconsequential to the word-alignment procedure (see the *Virtex-5 FPGA User Guide* for more details).

Table 10: Word Alignment in the DDR Receiver

Bitslip Cycle	Data Value (Hex)	Data Value (Bin)	Description of Bitslip operation
1	19	01 1001	–
2	0B	00 1011	Rotate 3 bits to right
3	16	01 0110	Rotate 1 bit to left
4	32	11 0010	Rotate 3 bits to right
5	25	10 0101	Rotate 1 bit to left
6	2C	10 1100	Rotate 3 bits to right

The FSM in the BIT\_ALIGN\_MACHINE module used to implement both bit and word alignment is shown in [Figure 14, page 19](#). The FSM is divided into five sections, loosely described as: finding the first transition, getting through the first transition, finding the second transition, returning to the center of the eye, and word alignment.

To get through the first transition effectively for all possible types of jitter, two methods are used. The first method pertains to random jitter. If there is a lot of random jitter at the sampling point, the samples generated are not stable. The algorithm detects this instability by comparing current samples to older samples and, therefore, knows where the transition begins and ends. But what if the jitter is extremely deterministic? The transition then has discreet crossing points, such that within the transition there is very stable, but incorrect, data. In this case, the algorithm does not sense any instability and falsely concludes that the sampling point is not in the transition. To address this case, apart from evaluating stability, the algorithm also evaluates the correctness of the data content by using the bitslip feature in the middle of the transition. For example, if the algorithm determines that the sampled data is stable, it then asserts bitslip to look for the correct data. If 0x2c is found within six assertions of bitslip, the sampling point is not in the transition. But if 0x2c is not found, the algorithm increments the data delay and repeats the transition test again.



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Figure 14: FSM in the BIT\_ALIGN\_MACHINE Module

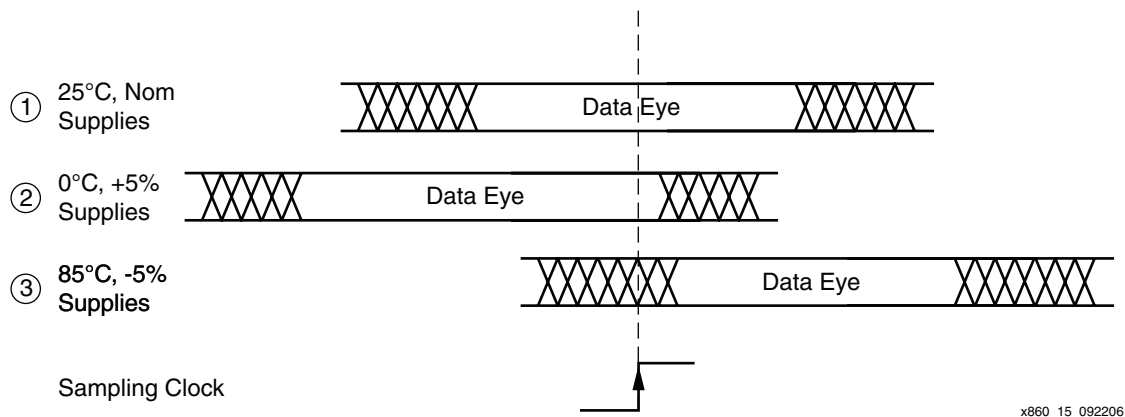
## Window Monitoring and RT\_WINDOW\_MONITOR

After the initial dynamic timing is established by BIT\_ALIGN\_MACHINE, the RT\_WINDOW\_MONITOR circuit ensures that the initial timing is adjusted to account for temperature and supply voltage drift during normal operation. The initial dynamic timing calibrates out error due to process, while the real-time window monitoring calibrates out error due to voltage and temperature. As a result, this reference design nullifies the three major sources of error in a system, commonly abbreviated as PVT (process, voltage, and temperature).

The initial alignment process of BIT\_ALIGN\_MACHINE depends upon the transmitter sending a known training pattern. The real-time window monitoring circuit that turns on after initialization does not require a training pattern; RT\_WINDOW\_MONITOR analyzes the user data and makes adjustments without causing any interruptions or bit errors in user data.

The architecture of the RT\_WINDOW\_MONITOR is shown in [Figure 8, page 11](#) as part of the greater RX interface. Since the RT\_WINDOW\_MONITOR does not have the luxury of using a training pattern and is not allowed to disrupt user data, it requires a monitor channel providing an identical copy of every data channel. The RT\_WINDOW\_MONITOR algorithm can then interrogate the monitor data eye, and apply adjustments to the master data eye if necessary. This method depends upon the fundamental assumption that both the master and monitor channels have identical delays, resulting in identical data eyes for both master and monitor channels.

After BIT\_ALIGN\_MACHINE completes the initial alignment, the sampling clock edge is aligned to the center of the data eye. In the absence of real-time adjustment, temperature and voltage variations over time cause drift to occur in the relationship between clock and data ([Figure 15](#)). During initialization under nominal temperature and voltage, the clock is centered in the data eye. At 85°C and -5% supply voltages, [Figure 15](#) shows that the clock is sampling invalid data.



**Figure 15: Without Real-time Adjustment, VT Variations can be Enough to Cause Errors at High Data Rates**

The purpose of the RT\_WINDOW\_MONITOR is to maintain a window of error-free IDELAY taps around the current tap setting. The size of the window is five IDELAY taps (two on either side of the current setting). If voltage or temperature vary such that errors begin to appear on either side of the window, RT\_WINDOW\_MONITOR responds by incrementing or decrementing the IDELAY setting of both the master and monitor channels to bring the window back into a valid region. By readjusting immediately when the window is compromised, the algorithm prevents actual user data from ever being sampled incorrectly.

The algorithm interrogates the five-tap window on the monitor channel by incrementing and decrementing the IDELAY tap settings of the monitor channel while leaving the tap settings of the data channel unchanged. The data and monitor channels are compared to one another at

every position in the window. If they are equal, the current tap position is error free; if they are different, the current tap position has errors.

**Note:** In Figure 8, page 11, the monitor channel is active Low because the output of the LVDS input buffer that drives the monitor is inverted. The monitor channel must be inverted again before it is compared to the data channel.

Figure 16 shows the operation of RT\_WINDOW\_MONITOR when the supply voltage drops gradually from nominal to  $-5\%$ . When the supply voltages are  $-1\%$  and  $-2\%$  of the nominal value, the data eye drifts but the algorithm does not adjust the sampling point because the five-tap window around the center tap setting are all error free. At  $-3\%$ , one of the taps in the five-tap window (the  $-2$  tap) takes errors. The algorithm responds by incrementing the delay of the data and monitor channels by one tap, causing all five taps in the window to be error free again. The same operation happens again at  $-4\%$  and  $-5\%$ . User data suffers no errors at any time during any of the six cases illustrated in Figure 16, evident by observing the dotted line in each of the data eyes indicating the current sampling position for user data. However, if the RT\_WINDOW\_MONITOR is disabled, the  $-5\%$  case in Figure 16 would show errors on user data.

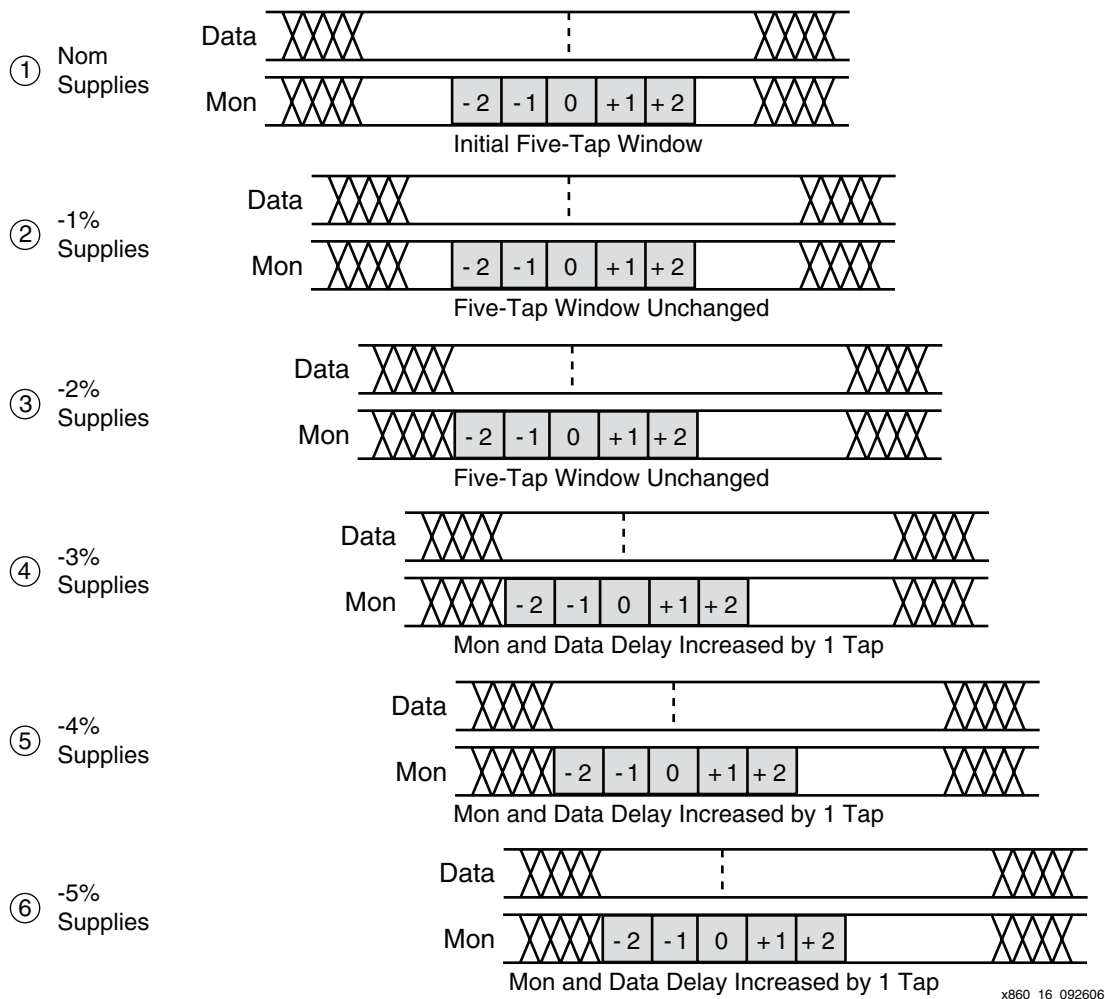


Figure 16: Operation of RT\_WINDOW\_MONITOR when Supply Voltages are Decreased

There are many possible cases to which the RT\_WINDOW\_MONITOR must react. For example, what if the data window is smaller than 5 taps? In this case, it is impossible to maintain five taps that are error free. In cases where the data eye becomes smaller than 5 taps, the algorithm "retreats" to a four tap window. If there are not four taps of data eye, the algorithm retreats to a three tap window, and so on. The RT\_WINDOW\_MONITOR polls all five positions

in the monitor window before making a decision about what to do. Table 11 shows a truth table of the behavior of RT\_WINDOW\_MONITOR for all possible states of the five-tap window.

Table 11: Truth Table of Actions for all Monitor Channel Window States

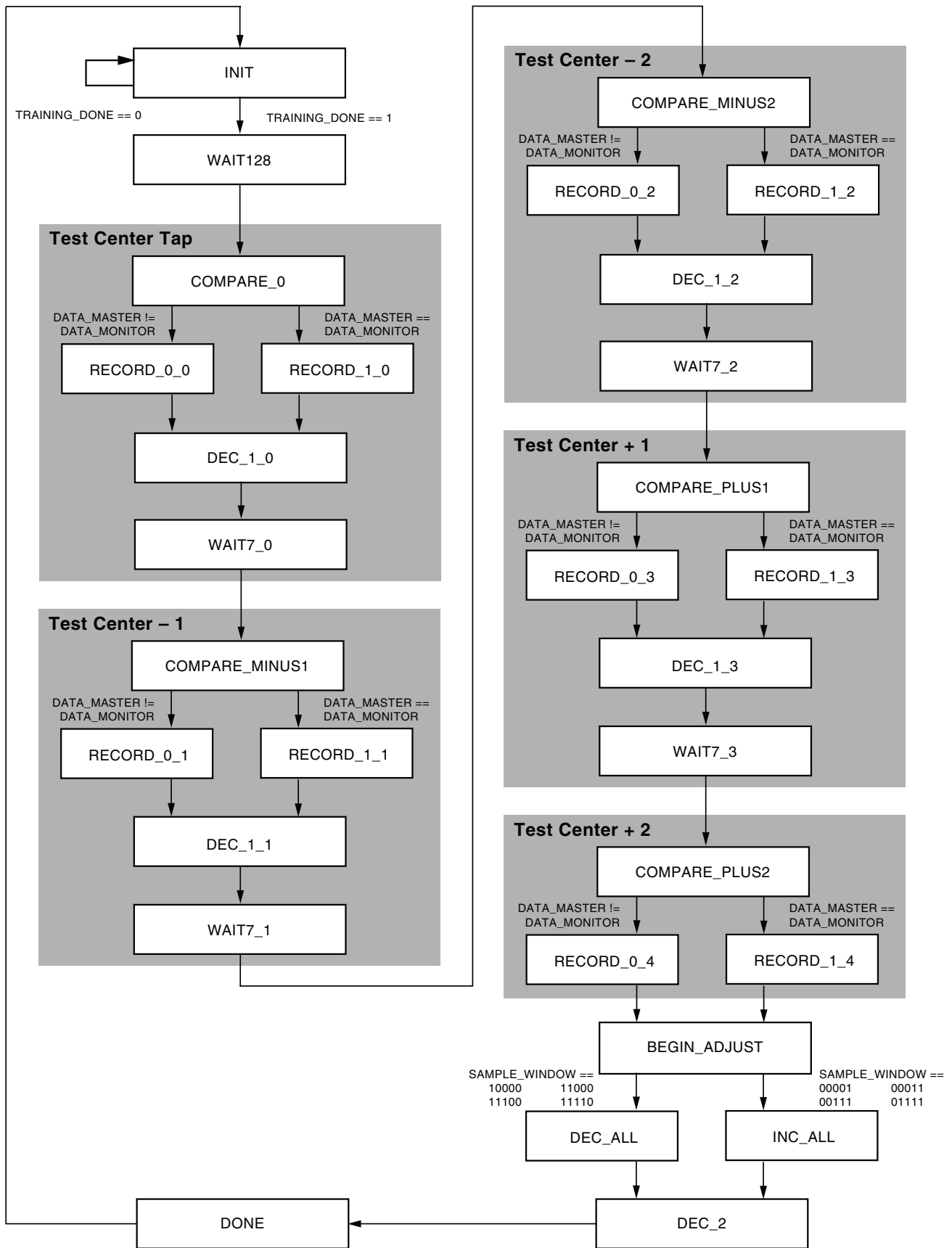
Monitor Channel Window					Action
-2	-1	0	+1	+2	
0	0	0	0	0	None
0	0	0	0	1	Increment data/mon delay
0	0	0	1	0	None
0	0	0	1	1	Increment data/mon delay
0	0	1	0	0	None
0	0	1	0	1	None
0	0	1	1	0	None
0	0	1	1	1	Increment data/mon delay
0	1	0	0	0	None
0	1	0	0	1	None
0	1	0	1	0	None
0	1	0	1	1	None
0	1	1	0	0	None
0	1	1	0	1	None
0	1	1	1	0	None
0	1	1	1	1	Increment data/mon delay
1	0	0	0	0	Decrement data/mon delay
1	0	0	0	1	None
1	0	0	1	0	None
1	0	0	1	1	None
1	0	1	0	0	None
1	0	1	0	1	None
1	0	1	1	0	None
1	0	1	1	1	None
1	1	0	0	0	Decrement data/mon delay
1	1	0	0	1	None
1	1	0	1	0	None
1	1	0	1	1	None
1	1	1	0	0	Decrement data/mon delay
1	1	1	0	1	None
1	1	1	1	0	Decrement data/mon delay
1	1	1	1	1	None

**Notes:**

- 0 = Errors; 1 = Error Free

The RT\_WINDOW\_MONITOR algorithm assumes that data flows continuously without any period of complete inactivity longer than a few minutes. The algorithm depends upon comparing the data and monitor channels to detect differences indicating errors at a given position in the monitor window. But if data is completely inactive and remains in the 0 state for several minutes, the algorithm can never detect the exact position of the monitor window within the data eye — if all bits are 0, there are no transitions to indicate the edges of the data eye. If the data eye drifts for any reason during data inactivity, the circuit does not detect the drift and fails to compensate. When data activity resumes, the sampling point could be outside of the data eye. Data can remain inactive for a period of several minutes, since it is unlikely that temperature or supply voltage could change drastically in such a small amount of time; however, several hours of inactivity could be problematic.

The full state machine of RT\_WINDOW\_MONITOR is shown in [Figure 17](#).



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Figure 17: State Machine of RT\_WINDOW\_MONITOR



## Interface Timing Budget

In addition to sampling the data as closely as possible to the center of the data eye, the actual size of the data eye is important. By accurately predicting the size of the data eye in the receiver, the overall performance ceiling of the interface can be inferred. This reference design removes the three principal sources of sampling error (PVT) in a receiver by employing the use of dynamic timing. Skew between channels is also removed from consideration by performing alignment separately on each channel of the interface. With the major sources of error removed from consideration, what are the limiting factors of this interface?

Duty cycle distortion in the transmitter and receiver clock networks is always a factor in DDR designs. Jitter caused by the transmission path and the capacitance of the receiver reduces the data eye width seen by the receiver. The IDELAY chain induces a predictable amount of pattern jitter on the data signal in the chain. Finally, the 78 ps resolution of the IDELAY tap chain becomes a limiting factor. Working with 78 ps increments, it is not possible to utilize the entire data eye, since inevitably some valid eye width is lost between two taps.

The ideal data eye width is the period of the data rate (for example,  $T_{\text{Bit\_Period}} = 1.00$  ns for 1000 Mb/s.). Both the transmitter and receiver circuits have sources of error that subtract from the ideal data eye. The equation for the eye width at the output of the transmitter is shown in [Equation 4](#).  $T_{\text{JITTER}}$  is the peak-to-peak jitter of the clock source driving the transmitter data bus and forwarded clock.  $T_{\text{DCD}}$  is the maximum duty cycle distortion of the clock tree driving the data bus and forwarded clock.

$$\text{DATA\_EYE\_WIDTH\_TX} = T_{\text{BIT\_PERIOD}} - T_{\text{JITTER}} - T_{\text{DCD\_BUFIO}} \quad \text{Equation 4}$$

[Equation 5](#) calculates the width of the data eye at the receiver flip-flops. Duty cycle distortion must be considered again on the receiver clock tree.  $T_{\text{IDELAYPAT\_JIT}}$  is the amount of pattern-dependent jitter that is accumulated in each tap of the IDELAY chain used. For a clock pattern,  $T_{\text{IDELAYPAT\_JIT}}$  is 0 ps/tap, peak to peak. For a data pattern with long and short run lengths of 0s and 1s (simulated by PRBS23),  $T_{\text{IDELAYPAT\_JIT}}$  has a finite value that must be considered in the timing budget.

$$\begin{aligned} \text{DATA\_EYE\_WIDTH\_RX} = & \text{DATA\_EYE\_WIDTH\_TX} - T_{\text{BOARD\_JITTER}} - \\ & T_{\text{DCD\_BUFIO}} - [T_{\text{IDELAYPAT\_JIT}} \times \text{IDELAY taps in datapath}] - T_{\text{QUANTIZATION\_ERR}} \end{aligned} \quad \text{Equation 5}$$

$T_{\text{BOARD\_JITTER}}$  includes jitter induced by receiver input capacitance, the parasitics of the physical datapath on the PCB, and the rise and fall times of the output driver.  $T_{\text{BOARD\_JITTER}}$  must be determined by simulation, as it varies as a function of frequency and for receivers of different types and vendors. On the ML550 evaluation board with a -1 speed-grade Virtex-5 device, the  $T_{\text{BOARD\_JITTER}}$  is measured at roughly 300 ps at 1000 Mb/s (assuming data content equivalent to PRBS23).  $T_{\text{QUANTIZATION\_ERR}}$ , or quantization error, is caused by the granularity of the IDELAY tap chain.

For example, [Equation 6](#) and [Equation 7](#) show the timing budget calculation for the DDR interface running at 1000 Mb/s in a -1 speed grade device on an ML550 evaluation board. Refer to the data sheet for the most current values. The TX interface is looped back to the RX interface on the same Virtex-5 FPGA, as shown in [Equation 2](#).

$$\text{DATA\_EYE\_WIDTH\_TX} = 1000 \text{ ps} - 25 \text{ ps} - 100 \text{ ps} = 875 \text{ ps} \quad \text{Equation 6}$$

$$\begin{aligned} \text{DATA\_EYE\_WIDTH\_RX} = & 875 \text{ ps} - 300 \text{ ps} - 100 \text{ ps} - [10 \text{ ps} \times 17 \text{ taps}] - 78 \text{ ps} \\ = & 227 \text{ ps} \end{aligned} \quad \text{Equation 7}$$

[Equation 7](#) indicates that there is at least 227 ps (or 3–4 IDELAY taps) of data valid window remaining valid under all conditions. This window would be much smaller (less than 0) if voltage and temperature variation were not calibrated out by RT\_WINDOW\_MONITOR (compare this calculation to the measurements in “Appendix,” [Table 18](#) through [Table 17](#)). There are three -1 devices tested at 1000 Mb/s, and each has 4, 3, and 3 taps, respectively, of eye width under all conditions.

Equation 8 and Equation 9 show the same timing budget calculation for the DDR interface running at 1.2 Gb/s in a -3 speed grade device on an ML550 evaluation board. On the ML550 with a -3 speed-grade Virtex-5 device, the  $T_{\text{BOARD\_JITTER}}$  is measured at roughly 200 ps at 1200 Mb/s (assuming data content equivalent to PRBS23).

$$\text{DATA\_EYE\_WIDTH\_TX} = 833 \text{ ps} - 25 \text{ ps} - 100 \text{ ps} = 708 \text{ ps} \quad \text{Equation 8}$$

$$\text{DATA\_EYE\_WIDTH\_RX} = 708 \text{ ps} - 200 \text{ ps} - 100 \text{ ps} - [10 \text{ ps} \times 13 \text{ taps}] - 78 \text{ ps} = 200 \text{ ps} \quad \text{Equation 9}$$

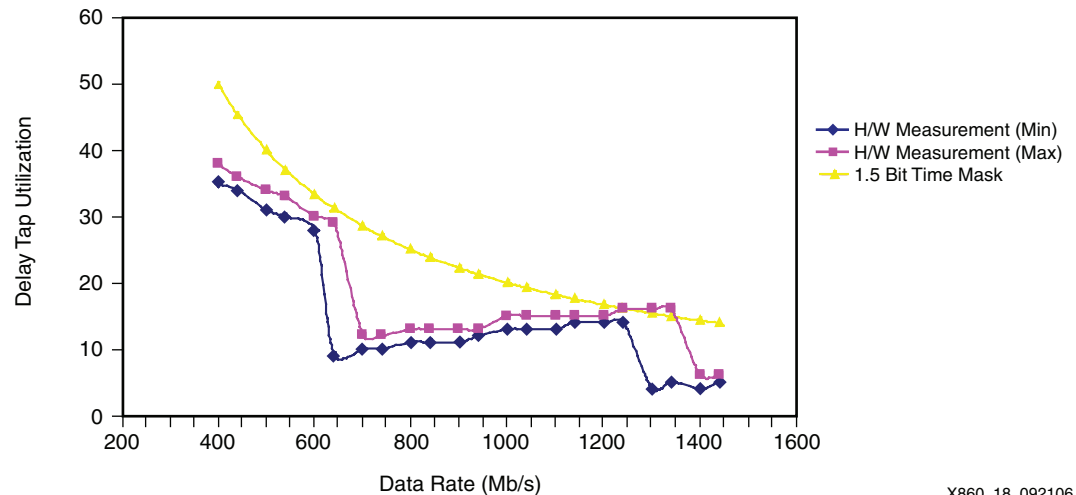
Equation 9 predicts that the DDR interface has 200 ps (or 3-4 IDELAY taps) of data window remaining valid under all conditions. In “Appendix,” Table 23 to Table 25, there are three -3 devices tested at 1200 Mb/s, each exhibiting 3, 3, and 4 taps, respectively, of eye width under all conditions.

Theoretically, the receiver should sample data correctly if the eye width at the receiver were as small as 1 ps. However, this is not a sound assumption. Referring back to Figure 16, page 21, the data and monitor channels are assumed to be perfectly matched in the time domain. In reality, there is some difference between the data and monitor channels. Characterization results show this difference to be no more than a single tap. In a scenario where the data and monitor path delays differ by 1 tap, what if there is only one or two taps of data valid window? It is possible for the monitor to run error free (satisfying the RT\_WINDOW\_MONITOR algorithm), while user data constantly takes errors. For this reference design to work properly for all devices, it is necessary to design for at least 3 taps of data valid window at the receiver, such that even if there is a single tap of difference between data and monitor channels, the data is still error free.

## Interface Characterization

By following the procedure illustrated in Figure 13, page 17, the bit-alignment algorithm should never insert more than approximately 1.5 bit times of delay on the data channels. The fewest number of delay taps should be used in the datapath because they produce a finite amount of degradation ( $T_{\text{DELAYPAT\_JIT}}$ ). The worst-case initial timing for the algorithm occurs when the clock samples just before the data transitions, as in the 600 Mb/s case in Figure 12, page 16. The algorithm must move all the way through the first eye to find the first transition (1 bit time) and then move halfway into the next eye to center the sampling point (0.5 bit time). This process produces a worst-case total delay insertion of 1.5 bit times.

The actual performance of the bit-alignment algorithm is characterized as a function of data rate in Figure 18, page 27. For all data rates, the expectation is that the tap settings of all 16 channels in the DDR receiver do not exceed approximately 1.5 bit times of delay. Both the maximum and minimum tap setting of all 16 channels is recorded for each data rate. This graph only shows the data for a single device. Comparing the 1.5 bit time mask to the actual settings, it is clear that the algorithm remains within the 1.5 bit time limit. At 1.3 Gb/s, the tap setting actually exceeds the mask by one tap (a negligible violation).



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Figure 18: Bit-Alignment Algorithm Performance

The maximum and minimum tap settings in Figure 18 generally stay within 3 to 4 taps of each other, except in the case of 640 Mb/s and 1300 Mb/s data rates. These data rates are "seams" in the inherent timing. At data rates below 640 Mb/s, the tap settings are in the range of 30 taps, and at data rates above 640 Mb/s, the tap settings are in the range of 12 taps. Referring back to Figure 12, page 16, it is clear why this "seam" occurs. As the data rate increases past 600 Mb/s, the initial sampling point of the inherent timing moves into a different data eye, creating a different starting point for the algorithm. At 640 Mb/s, some of the 16 channels start in one eye, while other channels start in the other eye. Fortunately this is not an issue because the single bit time of difference between the channels is resolved using bitslip.

Referring back to Figure 8, page 11, the clock channel goes through an IDELAY block with a default value of 0. After the data rate is chosen for a given design, this initial IDELAY value can be changed to a non-zero value to achieve more favorable inherent timing. For example, a design running at 620 Mb/s can use 30 IDELAY taps on the delay channels, each contributing a certain amount of jitter to the timing budget calculation. By setting the initial clock delay to 5 taps, the inherent timing moves across the seam shown in the 600 Mb/s range of Figure 18, causing the data channels to only use about 12 IDELAY taps. Only spectrally rich data patterns accumulate jitter in the IDELAY tap chain, so the clock IDELAY can be set to any value without diminishing the timing budget. This optimization is entirely optional and can be done after the design is running in hardware.

The DDR receiver is designed to remove skew between channels by aligning each channel individually. The ML550 board on which this reference design is characterized is designed to have minimal skew between channels. However, there is clearly a finite amount of skew between channels due to clock skew in the TX and RX BUFIO networks, package skew, and trace length tolerance on the ML550 board. Table 12, page 28 shows how the bit-alignment algorithm sets the delay for each channel differently to compensate for skew between channels. The table captures the range of settings among the 16 channels at specific data rates for a -2 device. If there were additional skew among the 16 channels, then the tap setting range would be larger to compensate for it. The algorithm is designed such that skew between channels should not diminish the performance of the interface. The range of tap settings differs for different devices and speed grades, but the magnitude should be approximately the same.

Table 12: Tap Setting Range For Various Data Rates Measured on a -2 Device

Data Rate (Mb/s)	Tap Setting Range	Compensated Skew
500	31–34	4 taps
600	28–30	3 taps
700	10–12	3 taps
800	11–13	3 taps
900	11–13	3 taps
1000	13–15	3 taps
1100	13–15	3 taps
1200	14–15	2 taps

Since the BIT\_ALIGN\_MACHINE only runs once immediately after reset, the resulting dynamic timing does not compensate for drift due to temperature and voltage. For this reason, the RT\_WINDOW\_MONITOR circuit is activated after the initial training of BIT\_ALIGN\_MACHINE completes. Table 13 shows the data valid window at the ISERDES registers in the DDR receiver. The eyes shown are collective eyes of all 16 channels. The BERT testbench configuration loops back the DDR transmitter to the DDR receiver. Using pattern generators and error detectors programmed to send and receive a pseudorandom bit sequence (PRBS23), the width of the data valid window is evaluated using pseudorandom data that closely resembles real user data.

In both test cases shown in Table 13, the BIT\_ALIGN\_MACHINE accurately places the sampling point in the center of the data eye at initialization under nominal conditions (indicated by the "C" in each test case). Table 13 shows in hardware the same timing window drift described in Figure 15.

The top half of Table 13 ("Without Real-Time Window Monitoring") shows the data valid window under all extreme conditions with the RT\_WINDOW\_MONITOR disabled. The drift of the data eye is evident at  $\pm 5\%$  supply voltage. From one extreme to the other, the total drift of the data window is five taps, or approximately 375 ps, representing the sampling error of the receiver. This value should be comparable to the data sheet parameter  $T_{\text{SAMP\_BUFIO}}$ . With the RT\_WINDOW\_MONITOR disabled, the sampling error counts against the timing budget and actually causes the interface to fail in three cases.

The bottom half of Table 13 ("With Real-Time Window Monitoring") shows the same measurement as the top half, except that the RT\_WINDOW\_MONITOR is enabled. The drift, or sampling error, that is very pronounced in the top half is not present in the bottom half because the RT\_WINDOW\_MONITOR adjusts the IDELAY tap settings to compensate for the propagation delay changes caused by voltage and temperature variation (compare the values in column "Center Tap Range" of Table 13. In "Without Real-Time Window Monitoring," the value does not change at all, but in "With Real-Time Window Monitoring," the number of taps changes according to the current conditions of temperature and voltage. The actual eye sizes in both cases are identical; it is only their position relative to the sampling point that the RT\_WINDOW\_MONITOR adjusts. In "With Real-Time Window Monitoring," all cases are passing with margin on either side of the current sampling point (refer to "Appendix," page 33 for characterization of other devices).

**Table 13: Measurement of Receiver Drift under Extreme Conditions at 1000 Mb/s with Window Monitoring Enabled and Disabled (S/N 2219, Speed Grade: -1)**

Condition	Center Tap Range	IODELAY Taps (1)(2)																
		-8	-7	-6	-5	-4	-3	-2	-1	0	+1	+2	+3	+4	+5	+6	+7	+8
<b>Without Real-Time Window Monitoring</b>																		
25°C, Nom Supplies	15–17	F	F	F	F	F	F	P	P	C	P	F	F	F	F	F	F	F
0°C, Nom Supplies	15–17	F	F	F	F	F	F	P	P	P	P	F	F	F	F	F	F	F
85°C, Nom Supplies	15–17	F	F	F	F	F	F	P	P	P	P	F	F	F	F	F	F	F
25°C, +5% Supplies	15–17	F	F	F	F	P	P	P	P	P	F	F	F	F	F	F	F	F
0°C, +5% Supplies	15–17	F	F	F	F	P	P	P	P	P	F	F	F	F	F	F	F	F
85°C, +5% Supplies	15–17	F	F	F	F	P	P	P	P	P	F	F	F	F	F	F	F	F
25°C, -5% Supplies	15–17	F	F	F	F	F	F	F	F	F	P	P	P	F	F	F	F	F
0°C, -5% Supplies	15–17	F	F	F	F	F	F	F	F	F	P	P	P	F	F	F	F	F
85°C, -5% Supplies	15–17	F	F	F	F	F	F	F	F	F	P	P	P	F	F	F	F	F
Conclusion	Errors caused by -5% variation in supply voltage.																	
<b>With Real-Time Window Monitoring</b>																		
25°C, Nom Supplies	15–17	F	F	F	F	F	F	P	P	C	P	F	F	F	F	F	F	F
0°C, Nom Supplies	15–17	F	F	F	F	F	F	P	P	P	P	F	F	F	F	F	F	F
85°C, Nom Supplies	15–17	F	F	F	F	F	F	P	P	P	P	F	F	F	F	F	F	F
25°C, +5% Supplies	13–16	F	F	F	F	F	P	P	P	P	P	F	F	F	F	F	F	F
0°C, +5% Supplies	13–16	F	F	F	F	F	P	P	P	P	P	F	F	F	F	F	F	F
85°C, +5% Supplies	13–15	F	F	F	F	F	P	P	P	P	P	F	F	F	F	F	F	F
25°C, -5% Supplies	17–19	F	F	F	F	F	F	F	P	P	P	F	F	F	F	F	F	F
0°C, -5% Supplies	17–19	F	F	F	F	F	F	F	P	P	P	F	F	F	F	F	F	F
85°C, -5% Supplies	17–19	F	F	F	F	F	F	F	P	P	P	F	F	F	F	F	F	F
Conclusion	Error free under all conditions when calibrated under nominal conditions to position C.																	

**Notes:**

1. IODELAY taps, where "0" is the reference tap determined by the bit align machine at nominal voltage and 25°C.
2. The real-time window monitor circuit continually adjusts the initial setting "C" to track out voltage and temperature variations.
3. P = Error-free transmission; F = Error in transmission; C = IODELAY tap position selected by bit-align machine under nominal conditions at 25°C.

## Pattern Dependence of Receiver Performance

Different types of data patterns have different electrical signatures (rise and fall times, jitter, eye symmetry, etc.). A pattern with very narrow spectral content (such as a clock pattern) moves very favorably through the link because the receiver frequency response has little effect on the signal integrity. However, a pattern with wide spectral content (such as real data and pseudorandom patterns) stresses the link's frequency response. If the frequency response is not flat across the entire spectrum of the data content, the signal integrity is degraded as a result. The amount of degradation measured is shown in [Table 14, page 31](#). The DDR transmitter is looped back to the DDR receiver, and different patterns are programmed to traverse the link. Performance is assessed by evaluating the integrity of those patterns in the receiver.

PRBS7 is a pseudorandom data pattern with a maximum run length of seven consecutive zeroes or ones. PRBS15 is defined as having a maximum run length of fifteen consecutive zeroes or ones. These limitations on run lengths limit the spectral content of the pattern. A PRBS15 pattern has greater spectral content than a PRBS7 pattern and, therefore, is a more

strenuous test for the link. PRBS29 is the most strenuous test in [Table 14](#). A clock pattern is effectively a PRBS1.

As predicted, [Table 14](#) shows that there is more degradation for data patterns with more spectral content. At 1000 Mb/s and below, the data eye closure is symmetrical. Symmetrical eye closure is desired because it does not change the center of the eye as determined by the bit-alignment algorithm. Above 1000 Mb/s, the eye closure becomes more asymmetrical, causing the center of the data eye to diverge from the calibrated center (by only 1 tap).

In every data rate shown in [Table 14](#), all significant pattern-dependent degradation is caused between PRBS1 (clock pat) and PRBS15. Between PRBS15 and PRBS29, there is no additional degradation recorded in any of the measurements.

Table 14: Link Performance for Various Types of Data Measured on a -2 Device

Pattern	IODELAY Taps (1)																		
	-8	-7	-6	-5	-4	-3	-2	-1	0	+1	+2	+3	+4	+5	+6	+7	+8	+9	
<b>Case: 600 Mb/s</b>																			
Clock Pat (0101)	P	P	P	P	P	P	P	P	C	P	P	P	P	P	P	P	P	P	P
Training Pat (0x2C)	P	P	P	P	P	P	P	P	C	P	P	P	P	P	P	P	P	P	F
PRBS7	P	P	P	P	P	P	P	P	C	P	P	P	P	P	P	P	P	P	F
PRBS15	F	P	P	P	P	P	P	P	C	P	P	P	P	P	P	P	P	F	F
PRBS23	F	P	P	P	P	P	P	P	C	P	P	P	P	P	P	P	P	F	F
PRBS29	F	P	P	P	P	P	P	P	C	P	P	P	P	P	P	P	P	F	F
<b>Case: 800 Mb/s</b>																			
Clock Pat (0101)	F	F	P	P	P	P	P	P	C	P	P	P	P	P	P	F	F	F	F
Training Pat (0x2C)	F	F	P	P	P	P	P	P	C	P	P	P	P	P	P	F	F	F	F
PRBS7	F	F	P	P	P	P	P	P	C	P	P	P	P	P	F	F	F	F	F
PRBS15	F	F	F	P	P	P	P	P	C	P	P	P	P	P	F	F	F	F	F
PRBS23	F	F	F	P	P	P	P	P	C	P	P	P	P	P	F	F	F	F	F
PRBS29	F	F	F	P	P	P	P	P	C	P	P	P	P	P	F	F	F	F	F
<b>Case: 1000 Mb/s</b>																			
Clock Pat (0101)	F	F	F	P	P	P	P	P	C	P	P	P	P	P	F	F	F	F	F
Training Pat (0x2C)	F	F	F	P	P	P	P	P	C	P	P	P	P	F	F	F	F	F	F
PRBS7	F	F	F	F	P	P	P	P	C	P	P	P	F	F	F	F	F	F	F
PRBS15	F	F	F	F	F	P	P	P	C	P	P	P	F	F	F	F	F	F	F
PRBS23	F	F	F	F	F	P	P	P	C	P	P	P	F	F	F	F	F	F	F
PRBS29	F	F	F	F	F	P	P	P	C	P	P	P	F	F	F	F	F	F	F
<b>Case: 1200 Mb/s</b>																			
Clock Pat (0101)	F	F	F	F	P	P	P	P	C	P	P	P	P	F	F	F	F	F	F
Training Pat (0x2C)	F	F	F	F	P	P	P	P	C	P	P	P	F	F	F	F	F	F	F
PRBS7	F	F	F	F	F	P	P	P	C	P	F	F	F	F	F	F	F	F	F
PRBS15	F	F	F	F	F	F	P	P	C	F	F	F	F	F	F	F	F	F	F
PRBS23	F	F	F	F	F	F	P	P	C	F	F	F	F	F	F	F	F	F	F
PRBS29	F	F	F	F	F	F	P	P	C	F	F	F	F	F	F	F	F	F	F
<b>Case: 1400 Mb/s</b>																			
Clock Pat (0101)	F	F	F	F	F	F	P	P	C	P	P	P	F	F	F	F	F	F	F
Training Pat (0x2C)	F	F	F	F	F	P	P	P	C	P	P	F	F	F	F	F	F	F	F
PRBS7	F	F	F	F	F	F	P	P	C	P	F	F	F	F	F	F	F	F	F
PRBS15	F	F	F	F	F	F	P	P	C	F	F	F	F	F	F	F	F	F	F
PRBS23	F	F	F	F	F	F	P	P	C	F	F	F	F	F	F	F	F	F	F
PRBS29	F	F	F	F	F	F	P	P	C	F	F	F	F	F	F	F	F	F	F

**Notes:**

1. Where 0 is the reference tap determined by the bit-align machine under nominal conditions at 25°C.
2. P = Error-free transmission; F = Error in transmission; C = IODELAY tap position selected by bit-align machine under nominal conditions at 25°C.

## Resetting the Interface

Several dependencies determine the order in which circuits should be reset in the interface. The receiver cannot begin the alignment algorithm if the transmitter is not sending the training pattern. The transmitter must be reset before the receiver, and time must be allowed for the training pattern to propagate across the link before the receiver comes out of reset. The receiver also cannot begin the alignment algorithm until IDELAYCTRL has recovered from reset, which could take hundreds of cycles. The recommended reset timing for the interface is shown in Figure 19. This reset timing is implemented in the BERT testbench for this interface.

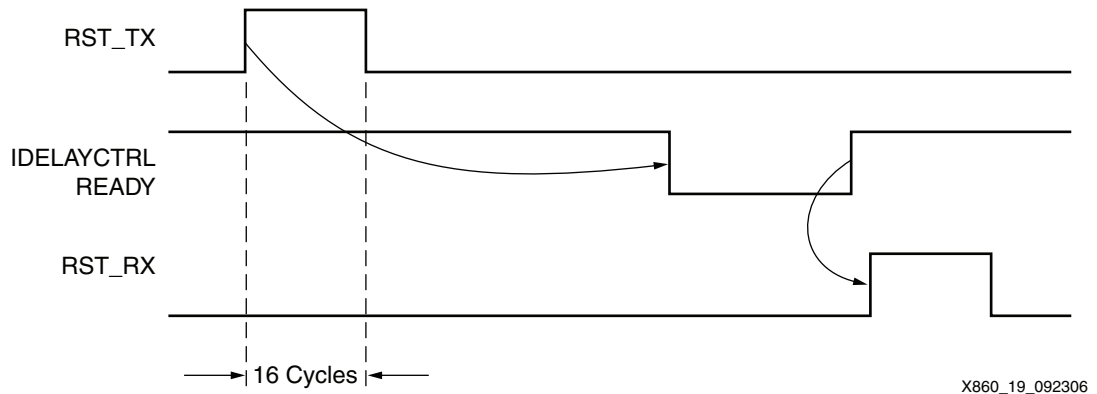


Figure 19: Recommended Interface Reset Timing

The TX reset (RST\_TX) is used to reset all TX circuitry and also IDELAYCTRL. The IDELAYCTRL reset is asynchronous so driving it with RST\_TX is acceptable. The minimum pulse width of IDELAYCTRL reset is 50 ns ( $T_{IDELAYCTRL\_RPW}$ ). For that reason, resets are held High for 16 clock cycles. The RX reset (RST\_RX) is used to reset all RX circuitry and is asserted when the IDELAYCTRL READY flag goes High, indicating that the IDELAY blocks are calibrated.

The timing of the READY flag in Figure 19 is a potential hazard. Most likely, it is High during a TX reset because it takes many cycles for IDELAYCTRL to deassert the READY flag. It is easy to make the mistake of resetting the receiver too early. To avoid this hazard, the RX reset should be asserted only after seeing a deassertion and reassertion of the READY flag.

## Reference Design

The files for this reference design can be found at:  
<https://secure.xilinx.com/webreg/clickthrough.do?cid=55681>

## Conclusion

Based on the design and characterization described in this document, the 16-Channel DDR reference design operates to the performance targets in Table 15 under all conditions of process, voltage and temperature. However, to meet these targets over voltage and temperature, the timing budget must be guaranteed according to the analysis in “Interface Timing Budget.” See “Appendix,” page 33 for further justification of the maximum performance recommendations in Table 15.

Table 15: Performance of 16-Channel DDR Interface with Window Monitoring

Speed Grade	Maximum Performance
-1	1.0 Gb/s
-2	1.25 Gb/s
-3	1.25 Gb/s



## Appendix

### Performance Characterization Data

Refer to “[Interface Characterization](#),” page 26 for explanations about how to interpret the data in the “[Appendix](#).” These tables show "collective" data eyes for the entire interface over process, voltage, and temperature (PVT). Three devices from each speed grade were selected for this characterization.

The calibrated center position of the eye (marked by the "C" in the tables below) varies slightly from channel to channel (due to small skews between channels). That range is referred to as center tap range. Analysis of [Table 18, page 35](#) through [Table 25, page 42](#) shows that the center tap range for slow and fast parts differ significantly at the same data rate (because the BIT\_ALIGN\_MACHINE algorithm adjusts for differences in speed).

All data in the “[Appendix](#)” is collected using the BERT testbench shown in [Figure 2, page 2](#). The data pattern is PRBS23 and the device/package is XC5VLX50T-FF1136. The transmission path for the cases shown in [Table 18](#) through [Table 25](#) is repeated for convenience:

TX → 5" FR-4 → SAMTEC QSE Conn → 12" Ribbon Cable → SAMTEC QSE Conn → 5" FR-4 → RX

A summary of these characterization results is shown in [Table 16](#). Each of the nine devices were tested to its maximum performance specification. When the interface is error free on all channels under all extreme conditions of temperature and voltage, the particular test case is designated by a P. A test case is marked FAIL when the interface suffered errors on any channel under any particular condition of voltage and temperature.

**Table 16: Summary of Interface Characterization Results**

Device (S/N)	Speed Grade	Window Monitoring Circuit	
		Disabled	Enabled
2194	-1	P	P
2219	-1	FAIL	P
2199	-1	FAIL	P
001	-2	FAIL	P
002	-2	P	P
003	-2	FAIL	P
004	-3	P	P
005	-3	FAIL	P
006	-3	P	P

**Notes:**

1. Specification for -1 speed grade is 1.0 Gb/s
2. Specification for -2 and -3 speed grade is 1.25 Gb/s

## Measurement of Receiver Drift Under Extreme Conditions

Table 17: S/N 2199, Speed Grade: -1, 1.0 Gb/s

Condition	Center Tap Range	IODELAY Taps <sup>(1)</sup>																
		-8	-7	-6	-5	-4	-3	-2	-1	0	+1	+2	+3	+4	+5	+6	+7	+8
<b>Without Real-time Window Monitoring</b>																		
25°C, Nom Supplies	13–14	F	F	F	F	F	F	P	P	C	P	P	F	F	F	F	F	F
0°C, Nom Supplies	13–14	F	F	F	F	F	F	P	P	P	P	P	F	F	F	F	F	F
85°C, Nom Supplies	13–14	F	F	F	F	F	F	P	P	P	P	P	F	F	F	F	F	F
25°C, +5% Supplies	13–14	F	F	F	F	P	P	P	P	P	P	F	F	F	F	F	F	F
0°C, +5% Supplies	13–14	F	F	F	F	P	P	P	P	P	P	F	F	F	F	F	F	F
85°C, +5% Supplies	13–14	F	F	F	F	P	P	P	P	P	P	F	F	F	F	F	F	F
25°C, -5% Supplies	13–14	F	F	F	F	F	F	F	F	F	P	P	P	P	F	F	F	F
0°C, -5% Supplies	13–14	F	F	F	F	F	F	F	F	F	P	P	P	P	F	F	F	F
85°C, -5% Supplies	13–14	F	F	F	F	F	F	F	F	F	P	P	P	P	F	F	F	F
CONCLUSION	Errors caused by -5% variation in supply voltage.																	
<b>With Real-time Window Monitoring<sup>(2)</sup></b>																		
25°C, Nom Supplies	13–14	F	F	F	F	F	F	P	P	C	P	P	F	F	F	F	F	F
0°C, Nom Supplies	13–15	F	F	F	F	F	F	P	P	P	P	F	F	F	F	F	F	F
85°C, Nom Supplies	13–15	F	F	F	F	F	F	P	P	P	P	F	F	F	F	F	F	F
25°C, +5% Supplies	12–13	F	F	F	F	F	P	P	P	P	P	F	F	F	F	F	F	F
0°C, +5% Supplies	12–13	F	F	F	F	P	P	P	P	P	P	F	F	F	F	F	F	F
85°C, +5% Supplies	12–13	F	F	F	F	F	P	P	P	P	P	F	F	F	F	F	F	F
25°C, -5% Supplies	14–16	F	F	F	F	F	F	F	F	P	P	P	F	F	F	F	F	F
0°C, -5% Supplies	14–16	F	F	F	F	F	F	F	F	P	P	P	F	F	F	F	F	F
85°C, -5% Supplies	14–16	F	F	F	F	F	F	F	P	P	P	P	F	F	F	F	F	F
CONCLUSION	Error free under all conditions when calibrated under nominal conditions to position C.																	

**Notes:**

- IODELAY taps, where "0" is the reference tap determined by the bit align machine at nominal voltage and 25°C.
- The real-time window monitor circuit continually adjusts the initial setting "C" to track out voltage and temperature variations.
- P = Error-free transmission; F = Error in transmission; C = IODELAY tap position selected by bit-align machine under nominal conditions at 25°C.

Table 18: S/N 2194, Speed Grade: -1, 1.0 Gb/s

Condition	Center Tap Range	IODELAY Taps (1)																
		-8	-7	-6	-5	-4	-3	-2	-1	0	+1	+2	+3	+4	+5	+6	+7	+8
<b>Without Real-time Window Monitoring</b>																		
25°C, Nom Supplies	13–14	F	F	F	F	F	P	P	P	C	P	P	F	F	F	F	F	F
0°C, Nom Supplies	13–14	F	F	F	F	F	P	P	P	P	P	P	F	F	F	F	F	F
85°C, Nom Supplies	13–14	F	F	F	F	F	P	P	P	P	P	P	F	F	F	F	F	F
25°C, +5% Supplies	13–14	F	F	F	P	P	P	P	P	P	F	F	F	F	F	F	F	F
0°C, +5% Supplies	13–14	F	F	F	P	P	P	P	P	P	F	F	F	F	F	F	F	F
85°C, +5% Supplies	13–14	F	F	F	P	P	P	P	P	P	F	F	F	F	F	F	F	F
25°C, -5% Supplies	13–14	F	F	F	F	F	F	F	P	P	P	P	P	F	F	F	F	F
0°C, -5% Supplies	13–14	F	F	F	F	F	F	F	F	P	P	P	P	F	F	F	F	F
85°C, -5% Supplies	13–14	F	F	F	F	F	F	F	P	P	P	P	P	F	F	F	F	F
CONCLUSION	Error free under all conditions when calibrated under nominal conditions to position C.																	
<b>With Real-time Window Monitoring(2)</b>																		
25°C, Nom Supplies	13–14	F	F	F	F	F	P	P	P	C	P	P	F	F	F	F	F	F
0°C, Nom Supplies	13–14	F	F	F	F	F	P	P	P	P	P	F	F	F	F	F	F	F
85°C, Nom Supplies	13–14	F	F	F	F	F	P	P	P	P	P	F	F	F	F	F	F	F
25°C, +5% Supplies	12–13	F	F	F	F	P	P	P	P	P	P	F	F	F	F	F	F	F
0°C, +5% Supplies	12–13	F	F	F	F	P	P	P	P	P	P	F	F	F	F	F	F	F
85°C, +5% Supplies	12–13	F	F	F	F	P	P	P	P	P	P	F	F	F	F	F	F	F
25°C, -5% Supplies	13–14	F	F	F	F	F	F	F	P	P	P	P	P	F	F	F	F	F
0°C, -5% Supplies	13–14	F	F	F	F	F	F	F	F	P	P	P	P	F	F	F	F	F
85°C, -5% Supplies	13–14	F	F	F	F	F	F	F	P	P	P	P	P	F	F	F	F	F
CONCLUSION	Error free under all conditions when calibrated under nominal conditions to position C.																	

**Notes:**

1. IODELAY taps, where "0" is the reference tap determined by the bit align machine at nominal voltage and 25°C.
2. The real-time window monitor circuit continually adjusts the initial setting "C" to track out voltage and temperature variations.
3. P = Error-free transmission; F = Error in transmission; C = IODELAY tap position selected by bit-align machine under nominal conditions at 25°C.

Table 19: S/N 2219, Speed Grade: -1, 1.0 Gb/s

Condition	Center Tap Range	IODELAY Taps (1)																
		-8	-7	-6	-5	-4	-3	-2	-1	0	+1	+2	+3	+4	+5	+6	+7	+8
<b>Without Real-time Window Monitoring</b>																		
25°C, Nom Supplies	15–17	F	F	F	F	F	F	P	P	C	P	F	F	F	F	F	F	F
0°C, Nom Supplies	15–17	F	F	F	F	F	F	P	P	P	P	F	F	F	F	F	F	F
85°C, Nom Supplies	15–17	F	F	F	F	F	F	P	P	P	P	F	F	F	F	F	F	F
25°C, +5% Supplies	15–17	F	F	F	F	P	P	P	P	P	F	F	F	F	F	F	F	F
0°C, +5% Supplies	15–17	F	F	F	F	P	P	P	P	P	F	F	F	F	F	F	F	F
85°C, +5% Supplies	15–17	F	F	F	F	P	P	P	P	P	F	F	F	F	F	F	F	F
25°C, -5% Supplies	15–17	F	F	F	F	F	F	F	F	F	P	P	P	F	F	F	F	F
0°C, -5% Supplies	15–17	F	F	F	F	F	F	F	F	F	P	P	P	F	F	F	F	F
85°C, -5% Supplies	15–17	F	F	F	F	F	F	F	F	F	P	P	P	F	F	F	F	F
CONCLUSION	Errors caused by -5% variation in supply voltage.																	
<b>With Real-time Window Monitoring(2)</b>																		
25°C, Nom Supplies	15–17	F	F	F	F	F	F	P	P	C	P	F	F	F	F	F	F	F
0°C, Nom Supplies	15–17	F	F	F	F	F	F	P	P	P	P	F	F	F	F	F	F	F
85°C, Nom Supplies	15–17	F	F	F	F	F	F	P	P	P	P	F	F	F	F	F	F	F
25°C, +5% Supplies	13–16	F	F	F	F	F	P	P	P	P	P	F	F	F	F	F	F	F
0°C, +5% Supplies	13–16	F	F	F	F	F	P	P	P	P	P	F	F	F	F	F	F	F
85°C, +5% Supplies	13–15	F	F	F	F	F	P	P	P	P	P	F	F	F	F	F	F	F
25°C, -5% Supplies	17–19	F	F	F	F	F	F	F	P	P	P	F	F	F	F	F	F	F
0°C, -5% Supplies	17–19	F	F	F	F	F	F	F	P	P	P	F	F	F	F	F	F	F
85°C, -5% Supplies	17–19	F	F	F	F	F	F	F	P	P	P	F	F	F	F	F	F	F
CONCLUSION	Error free under all conditions when calibrated under nominal conditions to position C.																	

**Notes:**

1. IODELAY taps, where "0" is the reference tap determined by the bit align machine at nominal voltage and 25°C.
2. The real-time window monitor circuit continually adjusts the initial setting "C" to track out voltage and temperature variations.
3. P = Error-free transmission; F = Error in transmission; C = IODELAY tap position selected by bit-align machine under nominal conditions at 25°C.

Table 20: S/N 001, Speed Grade: -2, 1.2 Gb/s

Condition	Center Tap Range	IODELAY Taps (1)																
		-8	-7	-6	-5	-4	-3	-2	-1	0	+1	+2	+3	+4	+5	+6	+7	+8
<b>Without Real-time Window Monitoring</b>																		
25°C, Nom Supplies	11–13	F	F	F	F	F	F	P	P	C	P	P	P	F	F	F	F	F
0°C, Nom Supplies	11–13	F	F	F	F	F	F	P	P	P	P	P	P	F	F	F	F	F
85°C, Nom Supplies	11–13	F	F	F	F	F	F	P	P	P	P	P	P	F	F	F	F	F
25°C, +5% Supplies	11–13	F	F	F	P	P	P	P	P	P	P	F	F	F	F	F	F	F
0°C, +5% Supplies	11–13	F	F	F	P	P	P	P	P	P	P	F	F	F	F	F	F	F
85°C, +5% Supplies	11–13	F	F	F	F	P	P	P	P	P	P	F	F	F	F	F	F	F
25°C, –5% Supplies	11–13	F	F	F	F	F	F	F	F	F	P	P	P	P	F	F	F	F
0°C, –5% Supplies	11–13	F	F	F	F	F	F	F	F	F	P	P	P	P	F	F	F	F
85°C, –5% Supplies	11–13	F	F	F	F	F	F	F	F	F	P	P	P	P	F	F	F	F
CONCLUSION	Errors caused by –5% variation in supply voltage.																	
<b>With Real-time Window Monitoring(2)</b>																		
25°C, Nom Supplies	11–13	F	F	F	F	F	P	P	P	C	P	P	F	F	F	F	F	F
0°C, Nom Supplies	11–13	F	F	F	F	F	F	P	P	P	P	P	F	F	F	F	F	F
85°C, Nom Supplies	12–14	F	F	F	F	F	P	P	P	P	P	P	F	F	F	F	F	F
25°C, +5% Supplies	11–12	F	F	F	P	P	P	P	P	P	P	F	F	F	F	F	F	F
0°C, +5% Supplies	11–13	F	F	F	P	P	P	P	P	P	P	F	F	F	F	F	F	F
85°C, +5% Supplies	11–13	F	F	F	F	P	P	P	P	P	P	F	F	F	F	F	F	F
25°C, –5% Supplies	12–14	F	F	F	F	F	F	F	F	P	P	P	P	F	F	F	F	F
0°C, –5% Supplies	12–13	F	F	F	F	F	F	F	F	P	P	P	P	F	F	F	F	F
85°C, –5% Supplies	12–14	F	F	F	F	F	F	F	F	P	P	P	P	F	F	F	F	F
CONCLUSION	Error free under all conditions when calibrated under nominal conditions to position C.																	

**Notes:**

1. IODELAY taps, where "0" is the reference tap determined by the bit align machine at nominal voltage and 25°C.
2. The real-time window monitor circuit continually adjusts the initial setting "C" to track out voltage and temperature variations.
3. P = Error-free transmission; F = Error in transmission; C = IODELAY tap position selected by bit-align machine under nominal conditions at 25°C.

Table 21: S/N 002, Speed Grade: -2, 1.2 Gb/s

Condition	Center Tap Range	IODELAY Taps (1)																
		-8	-7	-6	-5	-4	-3	-2	-1	0	+1	+2	+3	+4	+5	+6	+7	+8
<b>Without Real-time Window Monitoring</b>																		
25°C, Nom Supplies	12–13	F	F	F	F	F	P	P	P	C	P	P	F	F	F	F	F	F
0°C, Nom Supplies	12–13	F	F	F	F	F	P	P	P	P	P	P	F	F	F	F	F	F
85°C, Nom Supplies	12–13	F	F	F	F	F	P	P	P	P	P	P	F	F	F	F	F	F
25°C, +5% Supplies	12–13	F	F	F	F	P	P	P	P	P	P	F	F	F	F	F	F	F
0°C, +5% Supplies	12–13	F	F	F	F	P	P	P	P	P	P	F	F	F	F	F	F	F
85°C, +5% Supplies	12–13	F	F	F	F	P	P	P	P	P	P	F	F	F	F	F	F	F
25°C, -5% Supplies	12–13	F	F	F	F	F	F	F	P	P	P	P	P	P	F	F	F	F
0°C, -5% Supplies	12–13	F	F	F	F	F	F	F	P	P	P	P	P	P	F	F	F	F
85°C, -5% Supplies	12–13	F	F	F	F	F	F	F	F	P	P	P	P	P	F	F	F	F
CONCLUSION	Error free under all conditions when calibrated under nominal conditions to position C.																	
<b>With Real-time Window Monitoring(2)</b>																		
25°C, Nom Supplies	12–13	F	F	F	F	F	P	P	P	C	P	P	F	F	F	F	F	F
0°C, Nom Supplies	12–13	F	F	F	F	F	P	P	P	P	P	P	F	F	F	F	F	F
85°C, Nom Supplies	12–13	F	F	F	F	F	P	P	P	P	P	P	F	F	F	F	F	F
25°C, +5% Supplies	12–13	F	F	F	F	P	P	P	P	P	P	F	F	F	F	F	F	F
0°C, +5% Supplies	12–13	F	F	F	F	P	P	P	P	P	P	F	F	F	F	F	F	F
85°C, +5% Supplies	12–13	F	F	F	F	P	P	P	P	P	P	F	F	F	F	F	F	F
25°C, -5% Supplies	12–13	F	F	F	F	F	F	F	P	P	P	P	P	P	F	F	F	F
0°C, -5% Supplies	12–13	F	F	F	F	F	F	F	P	P	P	P	P	P	F	F	F	F
85°C, -5% Supplies	12–14	F	F	F	F	F	F	F	P	P	P	P	P	F	F	F	F	F
CONCLUSION	Error free under all conditions when calibrated under nominal conditions to position C.																	

**Notes:**

1. IODELAY taps, where "0" is the reference tap determined by the bit align machine at nominal voltage and 25°C.
2. The real-time window monitor circuit continually adjusts the initial setting "C" to track out voltage and temperature variations.
3. P = Error-free transmission; F = Error in transmission; C = IODELAY tap position selected by bit-align machine under nominal conditions at 25°C.

Table 22: S/N 003, Speed Grade: -2, 1.2 Gb/s

Condition	Center Tap Range	IODELAY Taps (1)																
		-8	-7	-6	-5	-4	-3	-2	-1	0	+1	+2	+3	+4	+5	+6	+7	+8
<b>Without Real-time Window Monitoring</b>																		
25°C, Nom Supplies	13–15	F	F	F	F	F	F	P	P	C	P	P	F	F	F	F	F	F
0°C, Nom Supplies	13–15	F	F	F	F	F	F	P	P	P	P	P	F	F	F	F	F	F
85°C, Nom Supplies	13–15	F	F	F	F	F	F	P	P	P	P	P	F	F	F	F	F	F
25°C, +5% Supplies	13–15	F	F	F	F	P	P	P	P	P	P	F	F	F	F	F	F	F
0°C, +5% Supplies	13–15	F	F	F	P	P	P	P	P	P	P	F	F	F	F	F	F	F
85°C, +5% Supplies	13–15	F	F	F	F	P	P	P	P	P	P	F	F	F	F	F	F	F
25°C, -5% Supplies	13–15	F	F	F	F	F	F	F	F	F	P	P	P	P	F	F	F	F
0°C, -5% Supplies	13–15	F	F	F	F	F	F	F	F	F	P	P	P	P	F	F	F	F
85°C, -5% Supplies	13–15	F	F	F	F	F	F	F	F	F	P	P	P	P	F	F	F	F
CONCLUSION	Errors caused by -5% variation in supply voltage.																	
<b>With Real-time Window Monitoring(2)</b>																		
25°C, Nom Supplies	13–15	F	F	F	F	F	F	P	P	C	P	P	F	F	F	F	F	F
0°C, Nom Supplies	13–15	F	F	F	F	F	F	P	P	P	P	P	F	F	F	F	F	F
85°C, Nom Supplies	13–14	F	F	F	F	F	F	P	P	P	P	P	F	F	F	F	F	F
25°C, +5% Supplies	12–14	F	F	F	F	P	P	P	P	P	P	F	F	F	F	F	F	F
0°C, +5% Supplies	12–14	F	F	F	F	P	P	P	P	P	P	F	F	F	F	F	F	F
85°C, +5% Supplies	12–14	F	F	F	F	F	P	P	P	P	P	F	F	F	F	F	F	F
25°C, -5% Supplies	15–16	F	F	F	F	F	F	F	P	P	P	P	F	F	F	F	F	F
0°C, -5% Supplies	15–16	F	F	F	F	F	F	F	P	P	P	P	F	F	F	F	F	F
85°C, -5% Supplies	15–16	F	F	F	F	F	F	F	P	P	P	F	F	F	F	F	F	F
CONCLUSION	Error free under all conditions when calibrated under nominal conditions to position C.																	

**Notes:**

- IODELAY taps, where "0" is the reference tap determined by the bit align machine at nominal voltage and 25°C.
- The real-time window monitor circuit continually adjusts the initial setting "C" to track out voltage and temperature variations.
- P = Error-free transmission; F = Error in transmission; C = IODELAY tap position selected by bit-align machine under nominal conditions at 25°C.

Table 23: S/N 004, Speed Grade: -3, 1.2 Gb/s

Condition	Center Tap Range	IODELAY Taps (1)																
		-8	-7	-6	-5	-4	-3	-2	-1	0	+1	+2	+3	+4	+5	+6	+7	+8
<b>Without Real-time Window Monitoring</b>																		
25°C, Nom Supplies	9–10	F	F	F	F	F	F	P	P	C	P	F	F	F	F	F	F	F
0°C, Nom Supplies	9–10	F	F	F	F	F	F	P	P	P	P	F	F	F	F	F	F	F
85°C, Nom Supplies	9–10	F	F	F	F	F	F	P	P	P	P	F	F	F	F	F	F	F
25°C, +5% Supplies	9–10	F	F	F	F	P	P	P	P	P	F	F	F	F	F	F	F	F
0°C, +5% Supplies	9–10	F	F	F	F	P	P	P	P	P	F	F	F	F	F	F	F	F
85°C, +5% Supplies	9–10	F	F	F	F	F	P	P	P	P	F	F	F	F	F	F	F	F
25°C, -5% Supplies	9–10	F	F	F	F	F	F	F	F	P	P	P	F	F	F	F	F	F
0°C, -5% Supplies	9–10	F	F	F	F	F	F	F	F	P	P	P	F	F	F	F	F	F
85°C, -5% Supplies	9–10	F	F	F	F	F	F	F	F	P	P	P	F	F	F	F	F	F
CONCLUSION	Error free under all conditions when calibrated under nominal conditions to position C.																	
<b>With Real-time Window Monitoring(2)</b>																		
25°C, Nom Supplies	9–10	F	F	F	F	F	F	F	P	C	P	F	F	F	F	F	F	F
0°C, Nom Supplies	9–10	F	F	F	F	F	F	F	P	P	P	F	F	F	F	F	F	F
85°C, Nom Supplies	9–10	F	F	F	F	F	F	F	P	P	P	F	F	F	F	F	F	F
25°C, +5% Supplies	8–9	F	F	F	F	F	F	P	P	P	P	F	F	F	F	F	F	F
0°C, +5% Supplies	8–9	F	F	F	F	F	F	P	P	P	P	F	F	F	F	F	F	F
85°C, +5% Supplies	8–9	F	F	F	F	F	F	P	P	P	P	F	F	F	F	F	F	F
25°C, -5% Supplies	11–12	F	F	F	F	F	F	F	P	P	P	F	F	F	F	F	F	F
0°C, -5% Supplies	11	F	F	F	F	F	F	F	P	P	P	F	F	F	F	F	F	F
85°C, -5% Supplies	11–12	F	F	F	F	F	F	F	P	P	P	F	F	F	F	F	F	F
CONCLUSION	Error free under all conditions when calibrated under nominal conditions to position C.																	

**Notes:**

1. IODELAY taps, where "0" is the reference tap determined by the bit align machine at nominal voltage and 25°C.
2. The real-time window monitor circuit continually adjusts the initial setting "C" to track out voltage and temperature variations.
3. P = Error-free transmission; F = Error in transmission; C = IODELAY tap position selected by bit-align machine under nominal conditions at 25°C.



Table 24: S/N 005, Speed Grade: -3, 1.2 Gb/s

Condition	Center Tap Range	IODELAY Taps (1)																
		-8	-7	-6	-5	-4	-3	-2	-1	0	+1	+2	+3	+4	+5	+6	+7	+8
<b>Without Real-time Window Monitoring</b>																		
25°C, Nom Supplies	11–12	F	F	F	F	F	F	P	P	C	P	P	F	F	F	F	F	F
0°C, Nom Supplies	11–12	F	F	F	F	F	F	P	P	P	P	P	F	F	F	F	F	F
85°C, Nom Supplies	11–12	F	F	F	F	F	F	P	P	P	P	P	F	F	F	F	F	F
25°C, +5% Supplies	11–12	F	F	F	F	P	P	P	P	P	F	F	F	F	F	F	F	F
0°C, +5% Supplies	11–12	F	F	F	F	P	P	P	P	P	F	F	F	F	F	F	F	F
85°C, +5% Supplies	11–12	F	F	F	F	F	P	P	P	P	P	F	F	F	F	F	F	F
25°C, –5% Supplies	11–12	F	F	F	F	F	F	F	F	P	P	P	P	F	F	F	F	F
0°C, –5% Supplies	11–12	F	F	F	F	F	F	F	F	P	P	P	P	F	F	F	F	F
85°C, –5% Supplies	11–12	F	F	F	F	F	F	F	F	F	P	P	P	F	F	F	F	F
CONCLUSION	Errors caused by –5% variation in supply voltage and 85°C.																	
<b>With Real-time Window Monitoring(2)</b>																		
25°C, Nom Supplies	11–12	F	F	F	F	F	F	P	P	C	P	P	F	F	F	F	F	F
0°C, Nom Supplies	11–12	F	F	F	F	F	F	P	P	P	P	F	F	F	F	F	F	F
85°C, Nom Supplies	11–13	F	F	F	F	F	F	P	P	P	P	F	F	F	F	F	F	F
25°C, +5% Supplies	9–11	F	F	F	F	F	P	P	P	P	P	F	F	F	F	F	F	F
0°C, +5% Supplies	9–11	F	F	F	F	F	P	P	P	P	P	F	F	F	F	F	F	F
85°C, +5% Supplies	10–11	F	F	F	F	F	F	P	P	P	P	F	F	F	F	F	F	F
25°C, –5% Supplies	11–13	F	F	F	F	F	F	F	P	P	P	P	F	F	F	F	F	F
0°C, –5% Supplies	11–13	F	F	F	F	F	F	F	P	P	P	P	F	F	F	F	F	F
85°C, –5% Supplies	12–14	F	F	F	F	F	F	F	P	P	P	F	F	F	F	F	F	F
CONCLUSION	Error free under all conditions when calibrated under nominal conditions to position C.																	

**Notes:**

1. IODELAY taps, where "0" is the reference tap determined by the bit align machine at nominal voltage and 25°C.
2. The real-time window monitor circuit continually adjusts the initial setting "C" to track out voltage and temperature variations.
3. P = Error-free transmission; F = Error in transmission; C = IODELAY tap position selected by bit-align machine under nominal conditions at 25°C.

Table 25: S/N 006, Speed Grade: -3, 1.2 Gb/s

Condition	Center Tap Range	IODELAY Taps (1)																
		-8	-7	-6	-5	-4	-3	-2	-1	0	+1	+2	+3	+4	+5	+6	+7	+8
<b>Without Real-time Window Monitoring</b>																		
25°C, Nom Supplies	9–10	F	F	F	F	F	F	P	P	C	P	P	F	F	F	F	F	F
0°C, Nom Supplies	9–10	F	F	F	F	F	F	P	P	P	P	P	F	F	F	F	F	F
85°C, Nom Supplies	9–10	F	F	F	F	F	F	P	P	P	P	P	F	F	F	F	F	F
25°C, +5% Supplies	9–10	F	F	F	F	P	P	P	P	P	P	F	F	F	F	F	F	F
0°C, +5% Supplies	9–10	F	F	F	F	P	P	P	P	P	P	F	F	F	F	F	F	F
85°C, +5% Supplies	9–10	F	F	F	F	F	P	P	P	P	P	F	F	F	F	F	F	F
25°C, -5% Supplies	9–10	F	F	F	F	F	F	F	P	P	P	P	P	F	F	F	F	F
0°C, -5% Supplies	9–10	F	F	F	F	F	F	F	P	P	P	P	P	F	F	F	F	F
85°C, -5% Supplies	9–10	F	F	F	F	F	F	F	F	P	P	P	P	F	F	F	F	F
CONCLUSION	Error free under all conditions when calibrated under nominal conditions to position C.																	
<b>With Real-time Window Monitoring(2)</b>																		
25°C, Nom Supplies	9–10	F	F	F	F	F	F	P	P	C	P	P	F	F	F	F	F	F
0°C, Nom Supplies	9–10	F	F	F	F	F	F	P	P	P	P	P	F	F	F	F	F	F
85°C, Nom Supplies	9–11	F	F	F	F	F	F	P	P	P	P	F	F	F	F	F	F	F
25°C, +5% Supplies	8–10	F	F	F	F	F	P	P	P	P	P	F	F	F	F	F	F	F
0°C, +5% Supplies	8–10	F	F	F	F	F	P	P	P	P	P	F	F	F	F	F	F	F
85°C, +5% Supplies	8–10	F	F	F	F	F	F	P	P	P	P	F	F	F	F	F	F	F
25°C, -5% Supplies	10–11	F	F	F	F	F	F	F	P	P	P	P	P	F	F	F	F	F
0°C, -5% Supplies	9–11	F	F	F	F	F	F	F	P	P	P	P	F	F	F	F	F	F
85°C, -5% Supplies	10–11	F	F	F	F	F	F	F	P	P	P	P	F	F	F	F	F	F
CONCLUSION	Error free under all conditions when calibrated under nominal conditions to position C.																	

**Notes:**

- IODELAY taps, where "0" is the reference tap determined by the bit align machine at nominal voltage and 25°C.
- The real-time window monitor circuit continually adjusts the initial setting "C" to track out voltage and temperature variations.
- P = Error-free transmission; F = Error in transmission; C = IODELAY tap position selected by bit-align machine under nominal conditions at 25°C.

## Revision History

The following table shows the revision history for this document.

Date	Version	Revision
10/13/06	1.0	Initial Xilinx release.
07/17/08	1.1	<ul style="list-style-type: none"><li>• Changed datapath delay to 78 ps throughout.</li><li>• Updated “<a href="#">Interface Clocking</a>,” page 6, and “<a href="#">Interface Timing Budget</a>,” page 25 sections.</li><li>• Updated <a href="#">Figure 6</a>, <a href="#">Table 3</a>, <a href="#">Table 15</a>, <a href="#">Table 16</a>, <a href="#">Table 20</a>, <a href="#">Table 21</a>, and <a href="#">Table 22</a>.</li></ul>

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